Lec -25

→ Before M.S: Solid State Physics.

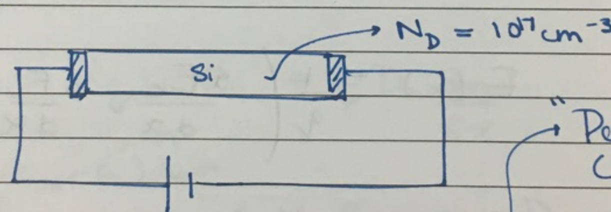
- Carriers, EB Diagram (Equ)
- R-G (SS) → uniform conc.
- Steady state with Spatial variation
  - Steady state → Diffusion
  - Spatial variation → Drift.
- Continuity eq^n + Poisson eq^n

→ Now: Application to Devices.

- Resistor
- Diodes 2 weeks
- BJT 1 week
- MOSFET 2 weeks.
- New Devices 1 week

7 Mini Quizzes More

Resistor



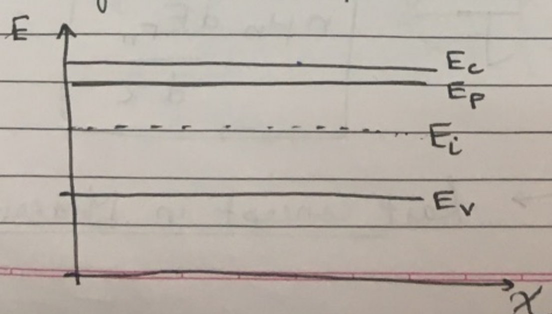
"Perfect Contact"

→ Metal contacts have no effect.

→ No Diffusion.

→ Constant Electric field

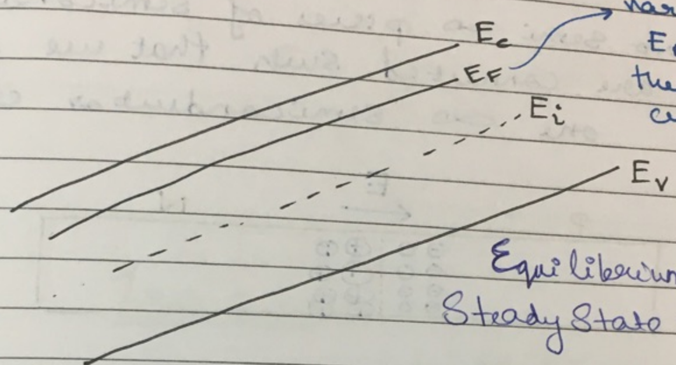
Band Diagram (At Equilibrium) (E = 0)



at E = 0

Steady State, $E \neq 0$

Slope sign is Imp.



variation of E_F tells us there is a current.

Equilibrium → No current

Steady State → Current ✓

Method

Start with E_c (or E_v just E in Gen.)

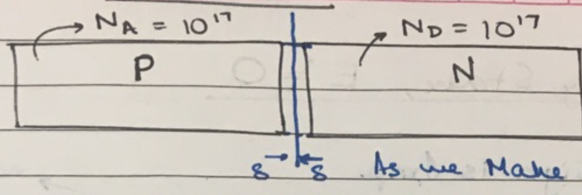
$= -q\,V(x)$

↳ Get $\vec{E}$

→ Are there Quasi Fermi Levels :

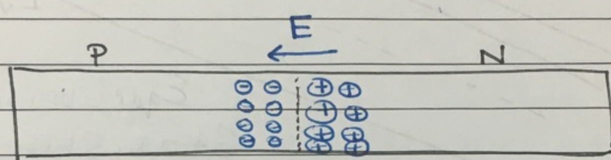
- No there is no split b/we the Quasi fermi levels.
- The n & p values are still given by the previous equations & values so we conclude no split b/we E_{Fn} & F_{Fp} Despite Steady State.

Diode



As we Make crystal contact

→ Two semi ∞ pieces of semiconductor are connected such that we get one ∞ semiconductor crystal.



→ As holes diffuse to the right and e^- diffuse to the left charge build up occurs & an electric field is set up.

→ Eventually the Generated Drift current offsets the existing diffusion current. 1)

~~Steps~~

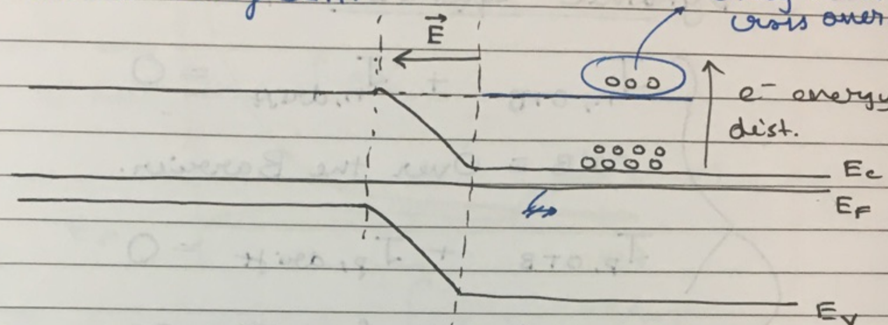
Steps

→ Diffusion
→ Generation / Uncovering of Ionic charges. **
→ Electric field.
→ Equilibrium ⇒ $J = 0$

Dynamic Eq ✓ Static ✗

2)

→ Band Diagram.



Lec - 26

→ Derive $I = I_0 \left(e^{qV/KT} - 1 \right)$

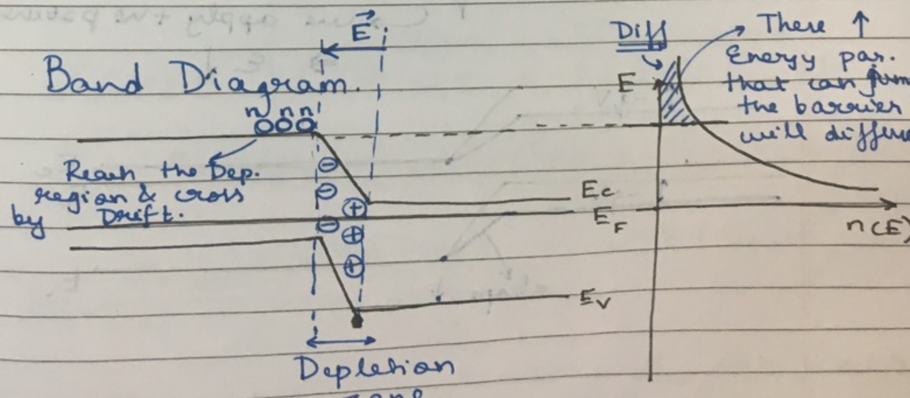
Text → SDF Chap, 5, 6 & 7

Recap

1) Even in Diode, $\frac{\delta E_F}{\delta x} = 0$ since

this comes from $J - J_N - J_P = 0$

2) Band Diagram.



Where, $n(E) = g(E)\, f(E)$

PAGE No. DATE / /

→ **Dynamic Equilibrium**

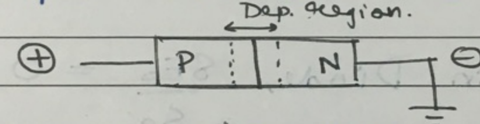
$$\left\{\begin{array}{l} J_{n,OTB} + J_{n,drift} = 0 \\ OTB \equiv \text{Over the Barrier.} \\ J_{p,OTB} + J_{p,drift} = 0 \end{array}\right.$$

→ our Model for $J = 0$

→ **Applying Bias**

- In our band diagram the energy levels we plot are all e^- energies.

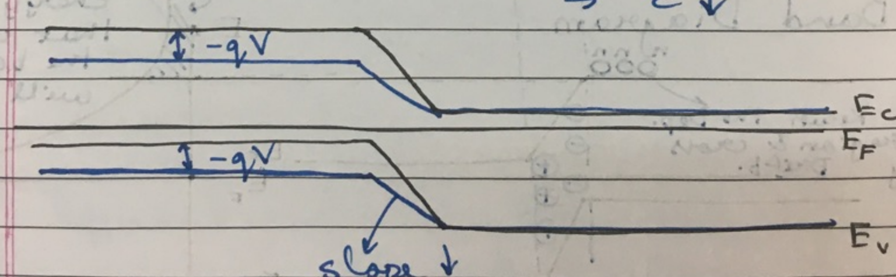
Dep. region

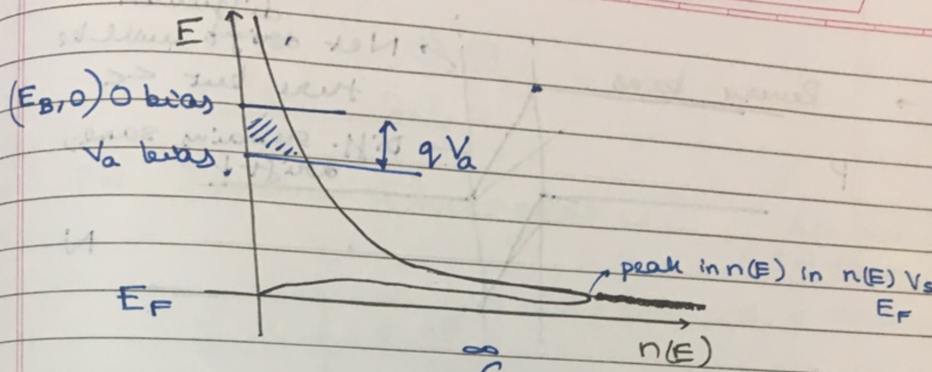


$\varepsilon = -qV$ (e^- energy)

↳ we apply +ve potential

$\Rightarrow \varepsilon \downarrow$





$$I_{OTB}(V) = \int_{E_{B,0}-qV_a}^{\infty} (\;) e^{-E/KT}$$

→ Here J_n drift, Minority carrier diffusion from right to left remains unchanged since it is limited by no. available.

→ Hence J_n drift = (In mag.) to J_{OTB} at $E_{B,0}$

$$J(V) = \int_{E_{B,0}-qV_a}^{\infty} (\;) e^{-E/KT}\, dE - \int_{E_{B,0}}^{\infty} (\;) e^{-E/KT}\, dE$$

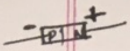
OTB (Std. State) − OTB (Equl.)

→ Assuming constant prefactor.

$$= (\;) \left(e^{E_{B,0}/KT} - e^{(E_{B,0}-qV_a)/KT}\right)$$

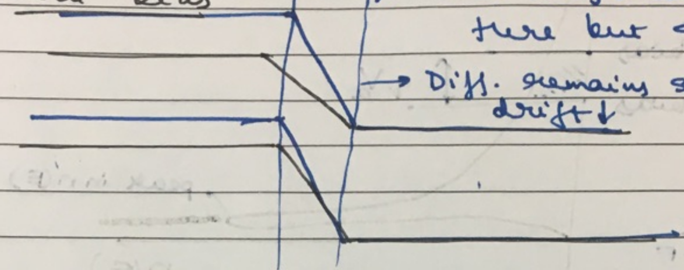
new

$$= (\;)\left[e^{qV_a/KT} - 1\right]$$



PAGE No.
DATE / /

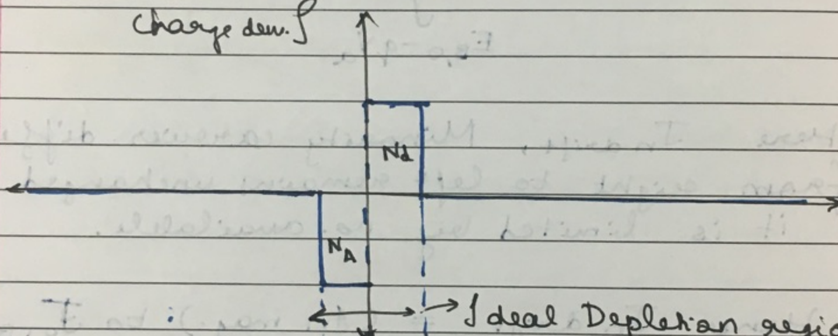
→ Reverse bias



→ Net ~~drift~~ diffusion will be there but <<

→ Diff. remains same, drift ↓

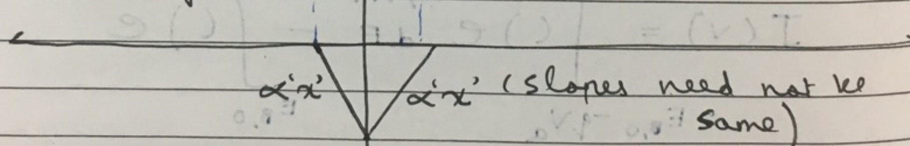
→ Charge Density Vs pos.



→ Ideal Depletion region, No mobile carriers.

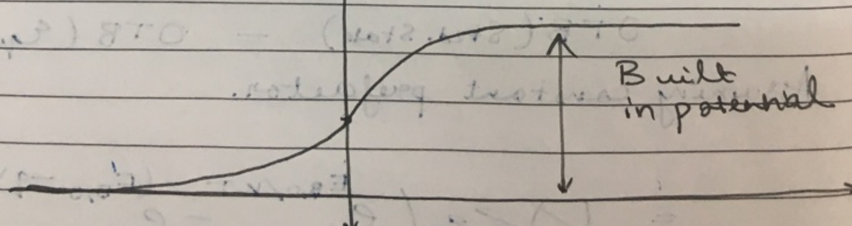
$\vec{E}$

→ Electric field



(slopes need not be same)

V



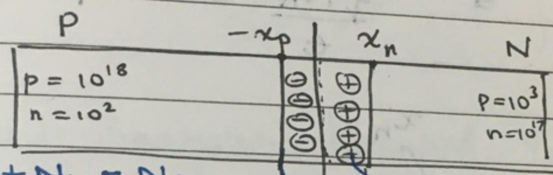
⊖ ⊕

Lec - 27

PN Junction Electrostatics

$$\rho = \begin{cases} \varepsilon \dfrac{dE}{dx} = -qN_A & -x_p < x < 0 \\ \phantom{\varepsilon \dfrac{dE}{dx}} = qN_D & 0 < x < x_n \end{cases}$$

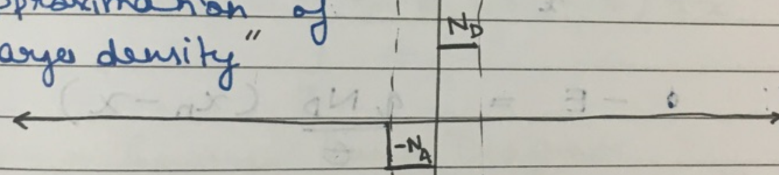
left end of dep. region



$\rho \to p - n + N_D - N_A$

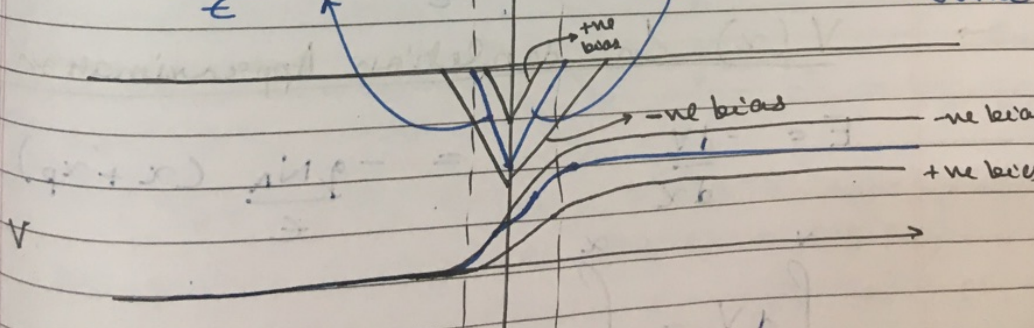
ρ "Called Depletion Approximation of Charge density"

Note Charge Density is Given by Majority carrier conc in that 1/2 ($10^{17}/10^{18}$) ∴ Ionic



E

$-\dfrac{qN_A}{\epsilon}(x + x_p)$ $\qquad$ $-\dfrac{qN_D}{\epsilon}(x_n - x)$



PAGE No. DATE / /

→ Calculation of Internal Electric Field

$$\int_0^E dE = \int_{-x_p}^{x} \frac{-qN_A}{\epsilon}\, dx$$

$\because \rho = \epsilon \frac{dE}{dx}$ & L.H.S of Dep. region

$$E = \frac{-qN_A}{\epsilon}(x + x_p) \quad -x_p \le x < 0$$

$$\int_E^0 dE = \int_x^{x_n} \frac{qN_D}{\epsilon}\, dx$$

$$0 - E = \frac{qN_D}{\epsilon}(x_n - x)$$

$$E = \frac{qN_D}{\epsilon}(x - x_n)$$

→ V(x) In depletion Approximation

$$E = -\frac{dV}{dx} = \frac{-qN_A}{\epsilon}(x + x_p)$$

$$\int_0^V dV = \int_{-x_p}^{x} \frac{qN_A}{\epsilon}(x + x_p)\, dx$$

$-x_p < x < 0$

$$V(x) = \frac{qN_A}{2\epsilon}(x+x_p)^2 \Big|_{-x_p}^{x}$$

~~Other side~~ $V(x) = \frac{qN_A}{2\epsilon}\left[(x+x_p)^2\right]$

$$\cancel{-\frac{qN_D}{2\epsilon}(x-x_n)^2}$$

~~Other side~~

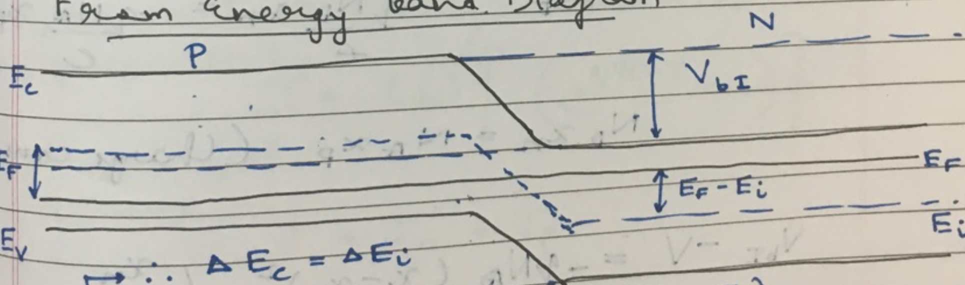
$$V(0) = \cancel{\frac{qN_A}{2\epsilon}x_p^2}$$

Voltages are relative.

→ To Get Barrier Potential V_{BI}

$$\int_{V}^{V_{bI}} dV = \int_{x}^{x_n} \frac{qN_D}{\epsilon}(x_n - x)\,dx$$

→ From Energy band Diagram



$\therefore \Delta E_c = \Delta E_i$

$= V_{bI} = (E_i - E_F)_{left} + (E_F - E_i)_{right}$ (out side depletion region)

On p side (out side depletion region)

$$p = N_A = n_i e^{(E_i - E_F)/kT}$$

L.H.S $\frac{kT}{q}\ln\left(\frac{N_A}{n_i}\right) = V_{left}$ (In terms of voltage)

$\frac{kT}{q}\ln\left(\frac{N_D}{n_i}\right) = V_{right}$

PAGE No.
DATE / /

$$V_{bI} = \frac{KT}{q} \ln\left(\frac{N_A N_D}{n_i^2}\right)$$

→ V inside in terms of x_n (R.H.S

$$\int_{V}^{V_{bI}} dV = \int_{x}^{x_n} \frac{qN_D}{\epsilon}(x_n - x)\,dx$$

~~V_{bI}-2V~~ & Equating E at $x=0$

$$-\frac{qN_D}{\epsilon}(x_n - x) = -\frac{qN_A}{\epsilon}(x + x_p)$$

$$-\frac{qN_D}{\epsilon}x_n = -\frac{qN_A}{\epsilon}x_p$$

$N_D x_n = N_A x_p$ (Charge cons.)

$$V_{bI} - V = -\frac{qN_D}{2\epsilon}(x - x_n)^2 \Big|_{x}^{x_n}$$

$$V_{bI} - V = 0 + \frac{qN_D}{2\epsilon}(x - x_n)^2$$

$V - V$

$$W_{\text{Depletion region}} = x_n + x_p = \left[\frac{2\epsilon V_{bi}}{q}\left(\frac{N_A+N_D}{N_A N_D}\right)\right]^{1/2}$$

$$V_{bI} = \frac{qN_D}{2\epsilon}(\cancel{x} - x_n)^2 + \frac{qN_A}{2\epsilon}(\cancel{x} + x_p)^2$$

$$V_{bI} = \frac{q}{2\epsilon}(N_D x_n^2 + N_A x_p^2)$$

$$= \frac{q}{2\epsilon} N_D x_n (x_n + x_p)$$

$$x_p = \frac{N_D}{N_A} x_n \qquad \frac{qN_D x_n^2}{2\epsilon}\left(1 + \frac{N_D}{N_A}\right) = V_{bI}$$

if $\frac{N_A}{N_D} >> 1 \Rightarrow$ {Entire Depletion region lies in N side}

$$x_n = \sqrt{\frac{N_A}{N_A+N_D} V_{bI} \times \frac{2\epsilon}{qN_D}}$$

$$x_p = \sqrt{\frac{N_D}{N_A+N_D} V_{bI} \times \frac{2\epsilon}{qN_A}}$$

$$x_n + x_p = \sqrt{\frac{V_{bI} \times 2\epsilon}{q}} \times \cancel{\left(\frac{1}{N_A+N_D}\right)^{1/2}} \times \left(\frac{N_A+N_D}{N_A N_D}\right)^{1/2}$$

Current Expression

→ From last class → estimate J_0

$$J = (J_0)\left[\left(e^{qV/kT} - 1\right)\right]$$

$$J = J_n + J_p$$

$$J_n = \frac{q n_i^2}{\tau_n N_A}\sqrt{D_n \tau_n}$$

$$J_p = \frac{q n_i^2}{\tau_p N_D}\sqrt{D_p \tau_p}$$

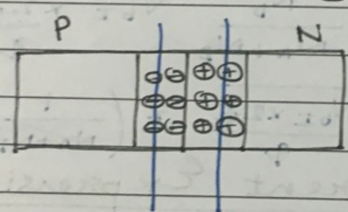
$\cancel{J_0} = \cancel{J_n} + \cancel{J_p}$

$$J = q\left(\frac{n_i^2}{N_D \tau_n}\sqrt{D_n \tau_n} + \frac{n_i^2}{N_D \tau_p}\sqrt{D_p \tau_p}\right)\left(e^{qV/kT} - 1\right)$$

$$= J_0 \left(\quad \cdot \quad \right)$$

Lec - 28

→ P-N Junction as Capacitor.

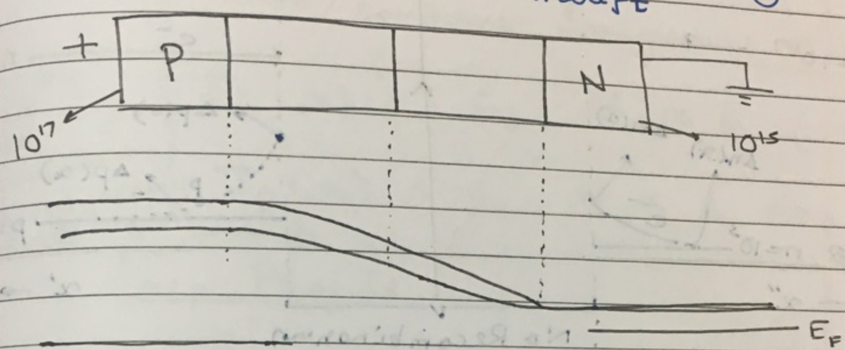


$-\frac{x_p}{2}$ $\frac{x_n}{2}$ → Assume Charge concentration at Mid-plane.

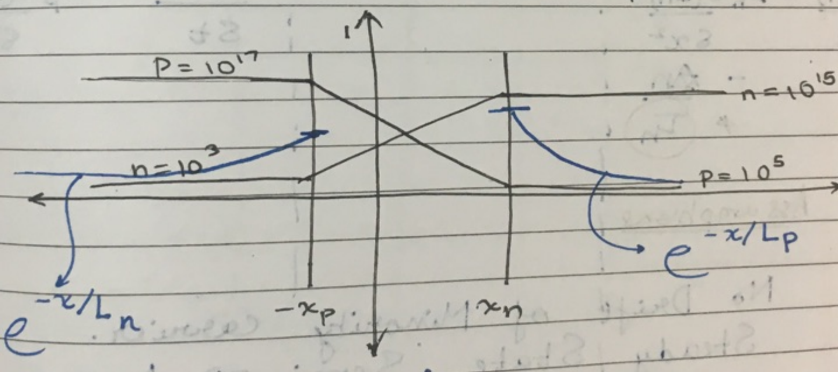
Current through Diode

At Eq.

$$J_{n\,diffusion} + J_{n\,drift} = 0$$

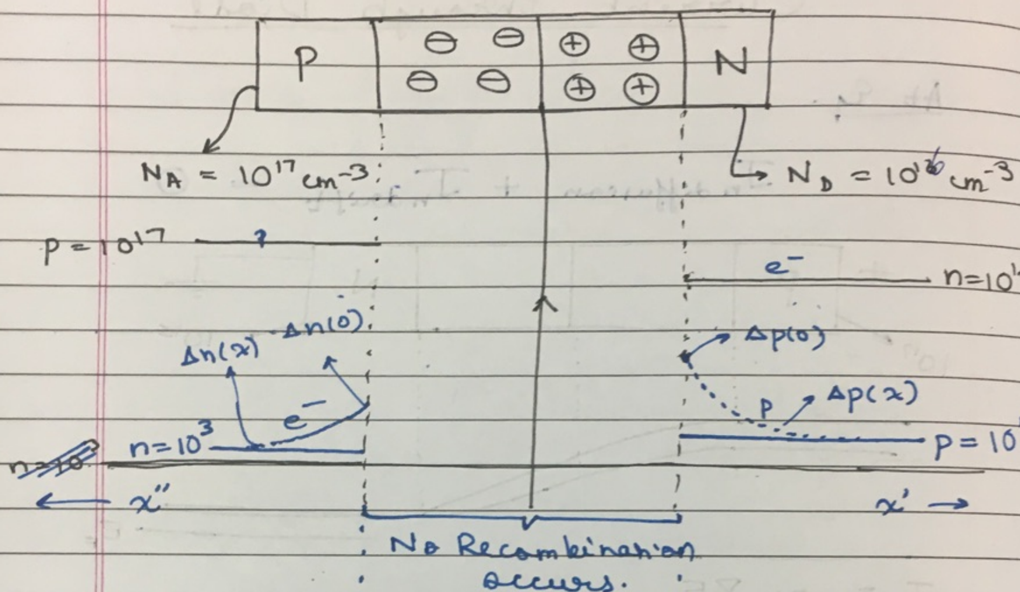


$J_p = p\mu \nabla E_{F_p}$ $\qquad p\uparrow \Rightarrow \nabla E_{F_p} \downarrow$



→ e^- may travel all the way to the contact or recombine in b/w, in both cases it contributes to the current.

Lec 30



$$\frac{\delta(\Delta n)}{\delta t} = D_n \frac{\delta^2(\Delta n)}{\delta x^2} - \frac{\Delta n}{\tau_n}$$

$$\frac{\delta(\Delta p)}{\delta t} = D_p \frac{\delta^2(\Delta p)}{\delta x^2}$$

Assumptions

→ No Drift of Minority carrier.

→ Steady State, Semi ∞ Approx.

$$\Delta n(x) = \Delta n(0)\, e^{-x''/L_n}$$

$$\Delta p(0)\, e^{-x'/L_p}$$

L_p / L_n → Diffusion lengths.

Current Determination.

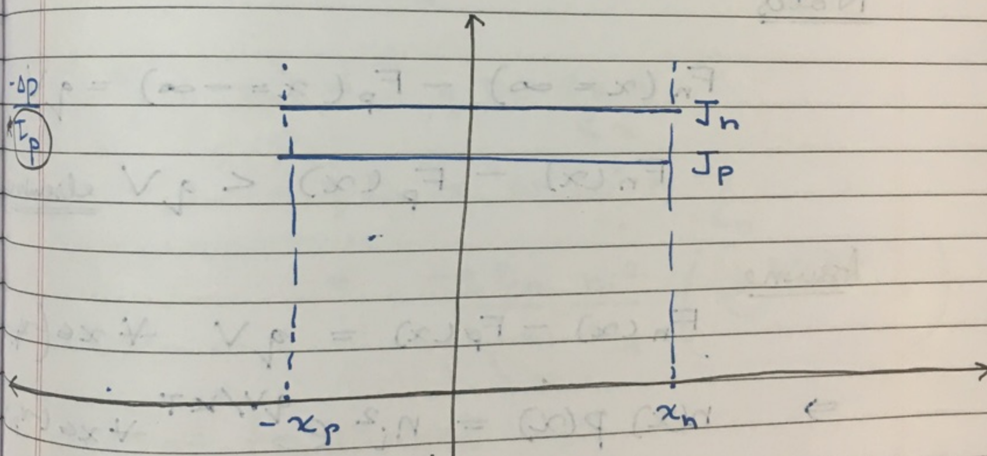
$$J = \underbrace{J_n(x) + J_p(x)}_{\text{vary}}$$

↳ same / constant irrespective of x

** No Accumulation, entire journey in dep. region covered.

$$\begin{cases} J_n(x) = C_1 & \forall\, x \in (-x_p, x_n) \\ J_p(x) = C_2 & \forall\, x \in (-x_p, x_n) \end{cases}$$

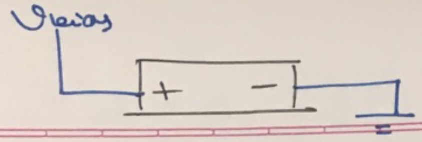
$J_{n/p}$ Profile



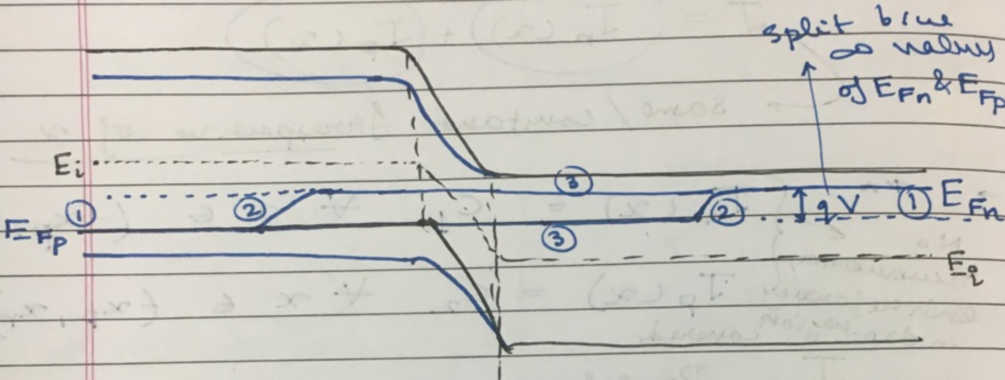
→ Using continuity of J_n / J_p

$$J = J_p(x_n) + J_n(-x_p)$$

↳ using constant J



→ Band Diagram in the presence of Bias



Notes

$$F_n(x=\infty) - F_p(x=-\infty) = qV$$

$$F_n(x) - F_p(x) < qV \text{ elsewhere}$$

Assume

$$F_n(x) - F_p(x) = qV \quad \forall x \in (-x_p, x_n)$$

$$\Rightarrow \quad n(x)\,p(x) = n_i^2 e^{qV/kT} \quad \forall x \in (-x_p, x_n)$$

At, $x = -x_p$, $p = N_A$, $n = \dfrac{n_i^2}{N_A} e^{qV/kT}$ 1)

2)

At, $x = x_n$, $n = N_D$, $P = \dfrac{n_i^2}{N_D} e^{qV/kT}$ 3)

Current Expression

$$J_n(-x_p) = -q D_n \frac{\delta(\Delta n)}{\delta x}\Bigg|_{x=-x_p}$$

$$\Delta n(-x_p) = n(-x_p) - n_o(-x_p)$$

$$= \frac{n_i^2}{N_A} e^{qV/kT} - \frac{n_i^2}{N_A}$$

$$= \frac{n_i^2}{N_A}\left(e^{qV/kT} - 1\right) = \Delta n(0)$$

$$J_n(-x_p) = q D_n \frac{\delta(\Delta n)}{\delta x}$$

$$= q D_n * \Delta n(0) \times \frac{-1}{L_n}$$

$$= \frac{-q D_n}{L_n} \frac{n_i^2}{N_A}\left(e^{qV/kT} - 1\right)$$

Food for thought

1) Connect Diode Across resistor, current?

2) Can we measure V_{bI} with a Voltmeter.

3) Reconcile the 2nd Derivation of current expression with 1st OTB derivation.

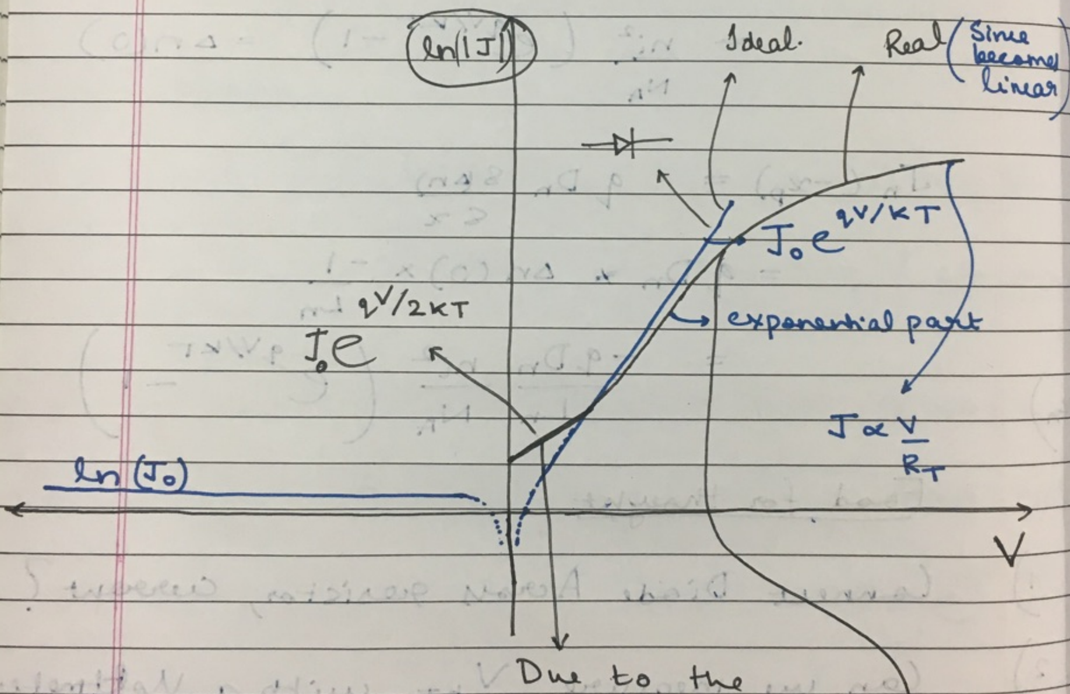
Lec - 32

Ideal Diode Vs. Real Diode

New Equations $(W = (\ ),\ V_{bI} = (\ ))$

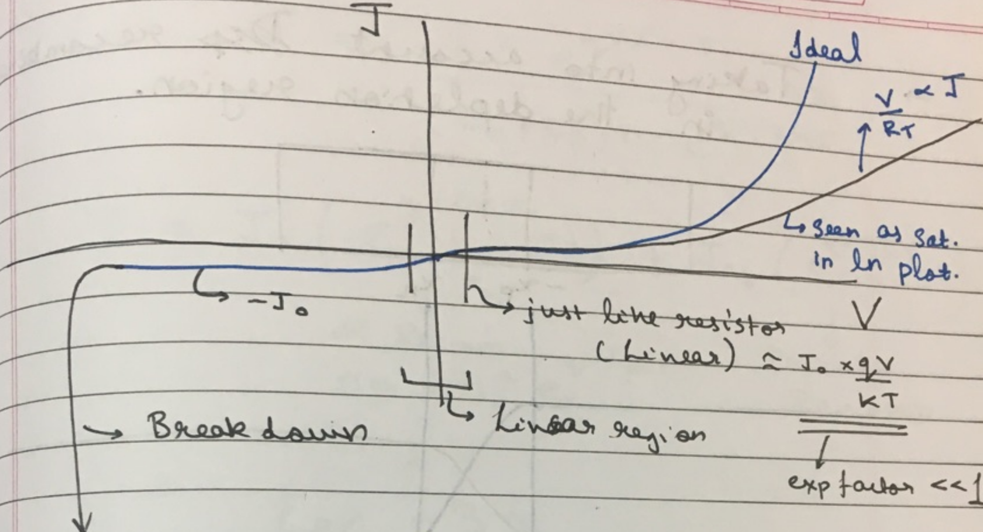
$$J = J_0 \left(e^{qV/KT} - 1 \right)$$

$$J_0 = q \left[\underbrace{\frac{n_i^2}{N_A} \frac{D_n}{L_n}}_{e^- \rightarrow P\text{ reg.}} + \underbrace{\frac{n_i^2}{N_D} \frac{D_p}{L_p}}_{p \rightarrow N\text{ reg.}} \right]$$

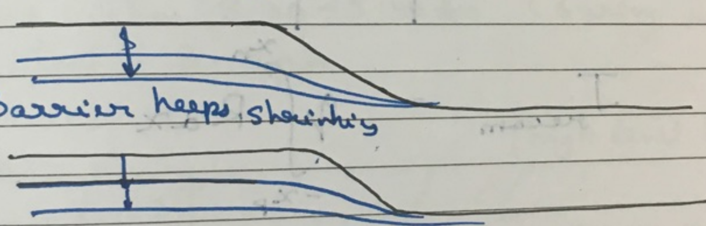


Due to the Recombination current.

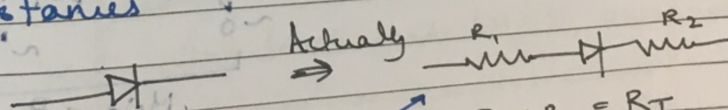
If High level Injection we get $e^{qV/2KT}$



→ from Band Diagram



→ As barrier keeps shrinking, all e^- can overcome the barrier and current is determined by resistances



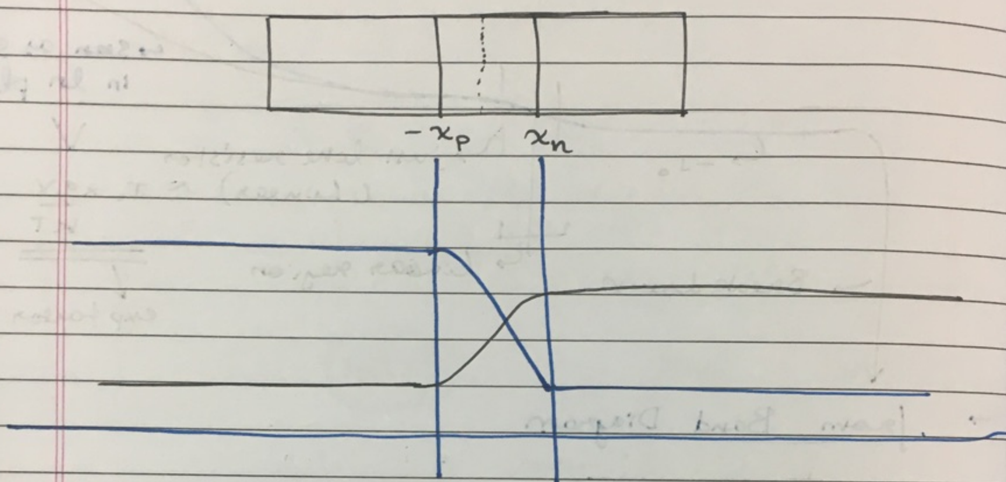
$R_1 + R_2 = R_T$

$$J \propto \frac{V}{R_T}$$

PAGE No.

DATE / /

→ Taking into account ~~Dsp~~ recombination in the depletion region.



$$J_{recom} = q\int_{-x_p}^{x_n} R\,dx$$

$$= \int \frac{n_i^2 \cdot e^{qV/kT} - n_i^2}{\tau_n(n + \underbrace{\cancel{n_1}}_{\sim 0}) + \tau_p(p + \underbrace{\cancel{p_1}}_{\sim 0})}$$

Mid - Band traps.

$$\int \frac{1}{\tau_n n + \tau_p p}\,dx$$

$n = p$, $np = n_i^2 e^{qV/kT}$

$n = n_i e^{qV/2kT}$

$$J = \frac{n_i^2 e^{qV/kT}}{(I_n + I_p)\, n_i e^{qV/2kT}} \quad \Delta x$$

$$J = J_0 \left(e^{qV/kT} - 1 \right) + J_{0_2} \left(e^{qV/2kT} - 1 \right)$$

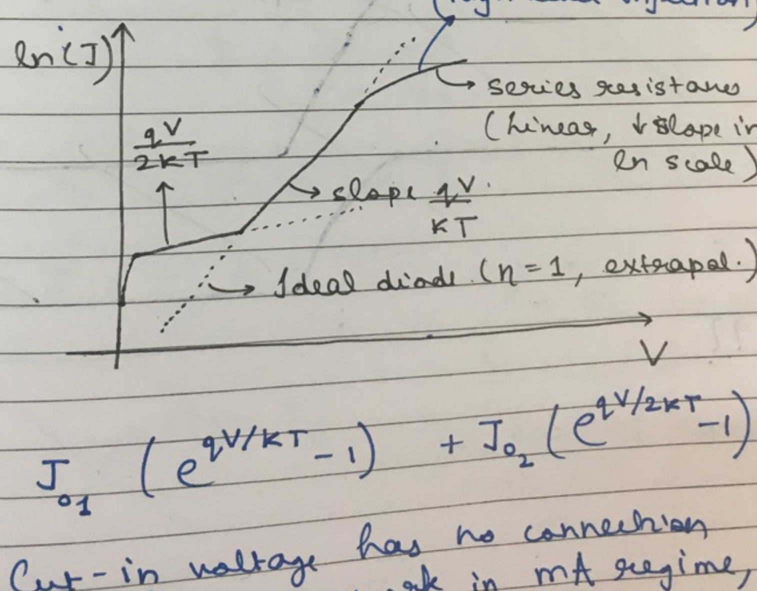
$\downarrow$ α Recom. $np = n_i^2 e^{qV/kT}$

$\downarrow$ Due to Recomb.

Lec - 33

Quiz : Thu 8:30 - 8:45 am (during lecture)
Tut : 3 - 4 pm

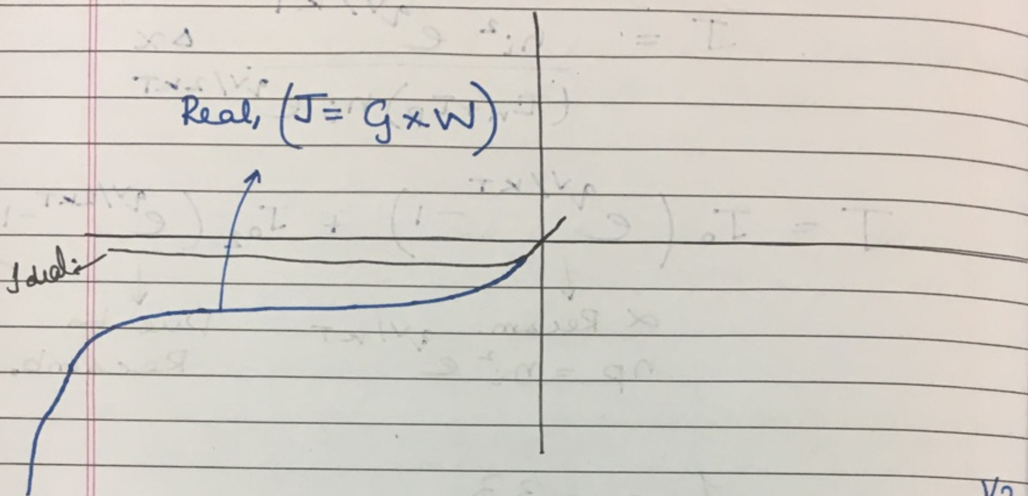
Recap



$$J = J_{0_1} \left(e^{qV/kT} - 1 \right) + J_{0_2} \left(e^{qV/2kT} - 1 \right)$$

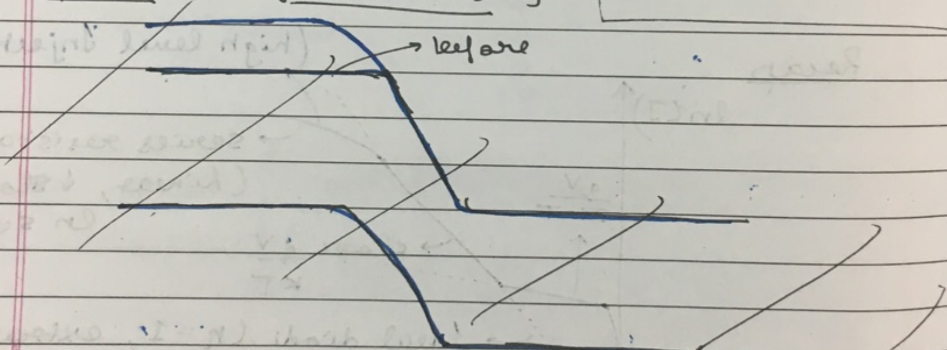
V_{on} / Cut-in voltage has no connection to V_{bI}. Since we work in mA regime, we define V_{on} to voltage where current crosses 1 mA. If we worked at μA scale value would be different.

Reverse Bias

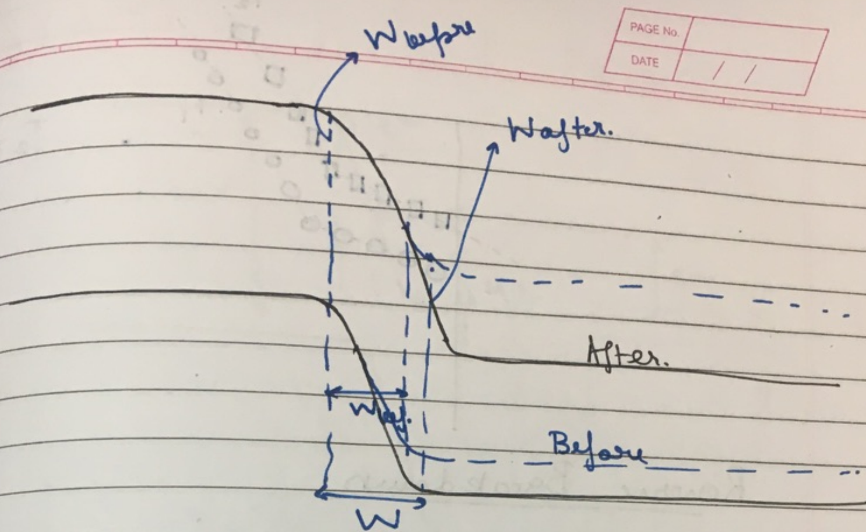


$$W = \frac{2\epsilon}{q}\left(\frac{1}{N_A} + \frac{1}{N_D}\right)\left(V_{bi} - \underbrace{V_{applied}}_{+ve/-ve}\right)\Bigg]^{1/2}$$

Application of Reverse bias



??



$$W \propto V_{APP}^{1/2}$$

Band Gap from temp. dependance

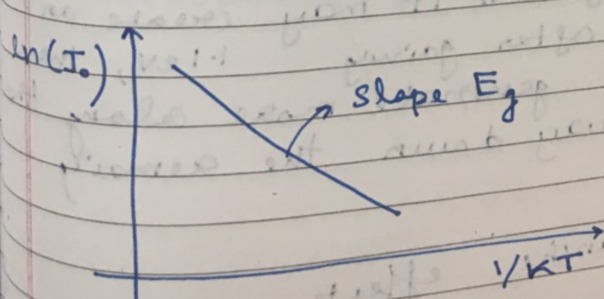
$$J_{o1}\left(e^{qV/KT}-1\right) + J_{o2}\left(e^{qV/2KT}-1\right)$$

$\propto n_i^2$ $\quad$ $\propto n_i$

$$J_{o1} = q\left(\frac{D_n}{L_n}\frac{n_i^2}{N_A} + \frac{D_p}{L_p}\frac{n_i^2}{N_D}\right)$$

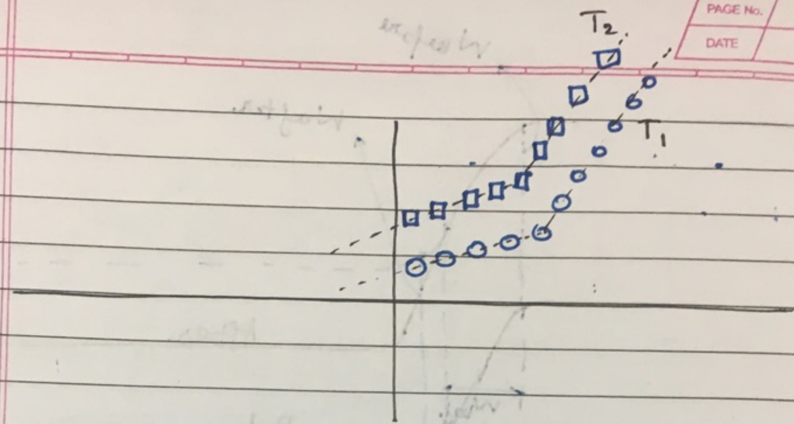
$$n_i^2 = (N_c N_v)\, e^{-E_g/KT}$$

$$J_o = A e^{-E_g/KT}$$



For J_{o2} we get $\frac{E_g}{2}$ slope since it has n_i dependance not n_i^2 depen.

PAGE No. DATE / /



$T_2 > T_1$

Reverse Breakdown

1) Avalanche Mechanism

→ $E_g \sim 1.1 eV$

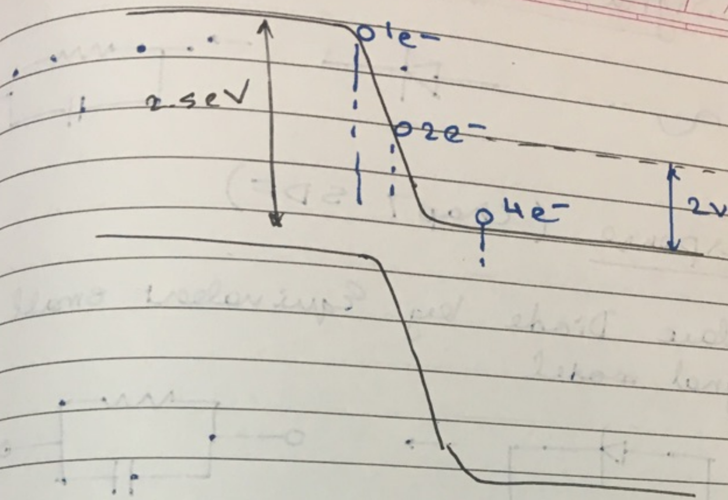
→ An e^- that goes down V_{bi} gains $K.E = eV_{bi}$

→ This energy is less than ~~F.B/~~ E_g in F.B/ no bias.

→ But with sufficient R.B, K.E > E_g & it can create e^- - hole pairs

→ ~~Mid~~ While going down the V_{bi} say of 2.5V, it may create an e^- hole pair after gaining 1.1eV, then will in turn generate more along the ~~the~~ their way down the remaining V_{bi}

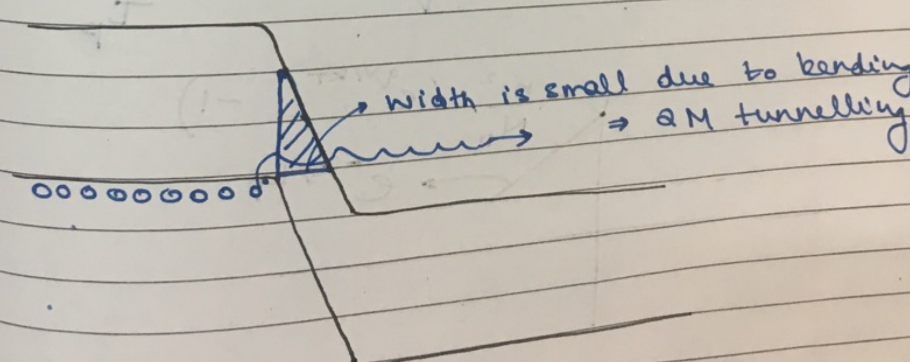
↳ Avalanche effect.



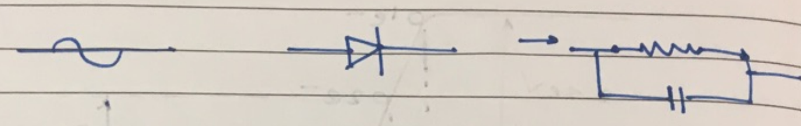
But in regular doped material this effect will be gradual & not at a fixed voltage.

Sudden Drop (Sharp breakdown)

Heavily doped $\quad p^{++} \rightarrow \sim 10^{20}\,cm^{-3}$
$\qquad\qquad\qquad n^{++} \rightarrow \sim 10^{20}\,cm^{-3}$

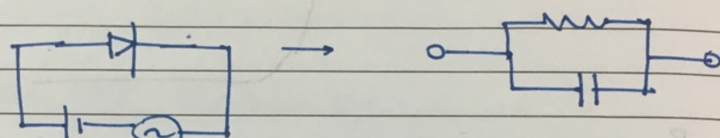


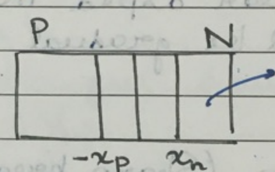
Signal Applied to Diode



AC Response ('Chap 7 SDF)

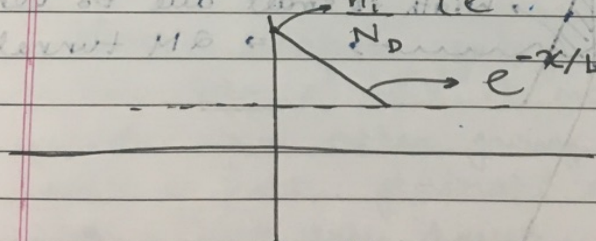
→ Replace Diode by Equivalent small signal model





→ Continuity Eqn.

$$\frac{\delta \Delta p}{\delta t} = -\frac{1}{q} \nabla \cdot J_p - \frac{\Delta p}{\tau_p}$$



$$Q_p = q \int_{x_n}^{\infty} \Delta p(x)\, dx = ?$$

Q_p ↓ Charge due to excess Minority carriers.

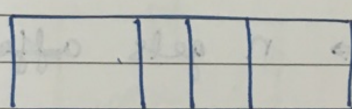
(Multiply throughout by q)

$$q\int_{x_n}^{\infty} \frac{\delta(\Delta p)}{\delta t}\,dx = \int_{x_n}^{\infty} -\nabla\cdot J_p\,dx - \int_{x_n}^{\infty} \frac{q\Delta p}{\tau_p}\,dx$$

$$\Rightarrow \frac{Q_p}{\tau_p} = q\int_{x_n}^{\infty} \Delta p(x)\,dx =$$

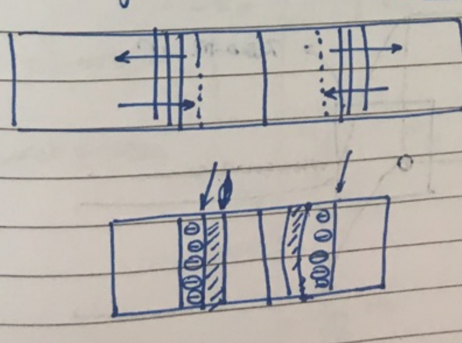
$$\frac{n_i^2}{N_D}\frac{L_p}{\tau_p}\left(e^{qV/kT}-1\right)$$

$$\cancel{\frac{Q_p}{\tau_p} =} \quad \frac{\delta Q_p}{\delta t} = -\frac{Q_p}{\tau_p} - \int_{x_n}^{\infty}(\nabla\cdot J_p)\,dx$$



small signal

When we apply small signal, depletion region width gets modulated.



$$C = \frac{\epsilon}{W}$$

→ We get Voltage dependant Capacitor

→ High Level Injection

$$np = n_i^2 e^{qV_a/KT}$$

$$p \approx \frac{n_i^2}{N_D} e^{qV_a/KT}$$

usually valid

But at high level injection

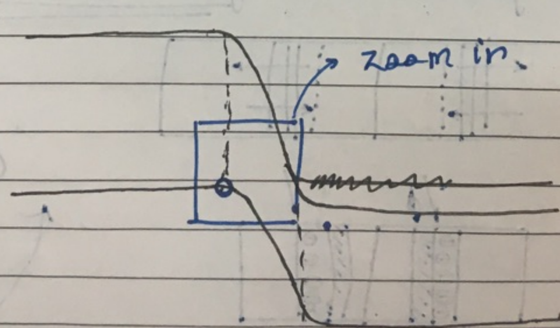
$$p - n + N_D^+ = 0$$

if $p >> N_D$

⇒ n gets ~~affected~~ affected

→ Zener Breakdown

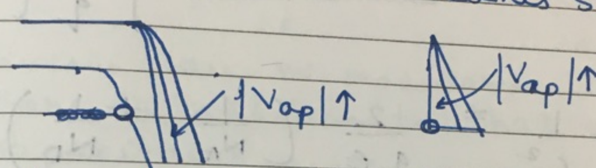
→ Quantum tunnelling breakdown.



Slope $\propto |\vec{E}|$

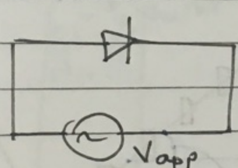
$|\vec{E}| \propto \dfrac{V_{ap}}{W}$, $\quad W \approx V_{ap}^{1/2}$

$\Rightarrow |\vec{E}| \uparrow \Rightarrow$ becomes steeper



→ P(tunnelling) ↑ as V_{ap} ↑

AC Response (Rev. Bias)

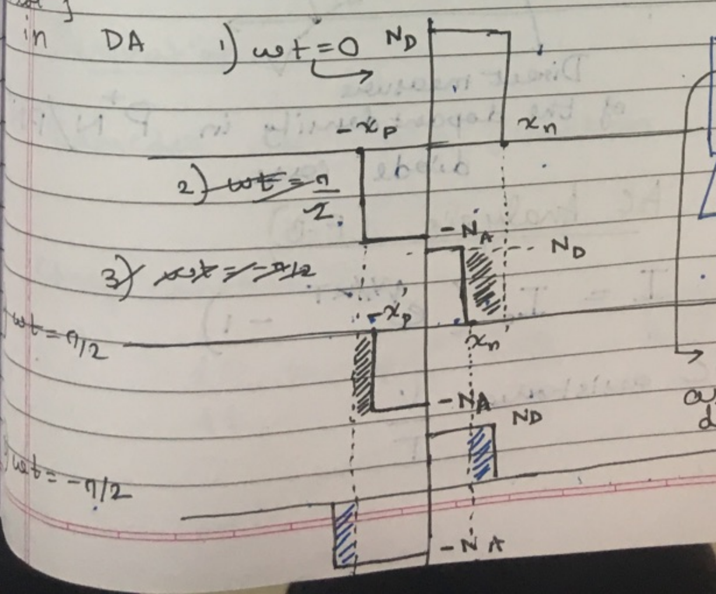


$\rho = p - n + N_D - N_A$

$V_{app} = V_{DC} + v$, $\quad V_{DC} = -2V$

$v = 10mV \sin(\omega t)$

Plot ρ in DA



$\boxed{C = \dfrac{\epsilon}{W}}$

→ capacitance per cm^{-2}

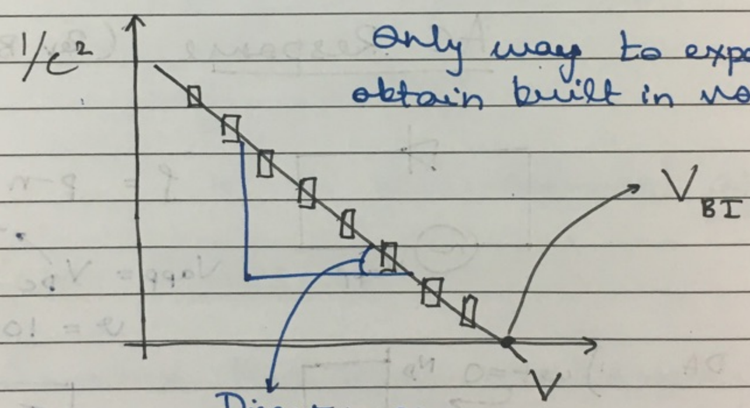
→ may be used as a voltage dependant capacitance

→ Built in voltage from C per cm^{-2}

$$C = \frac{\epsilon}{W}$$

$$C = \cancel{\epsilon} \quad \epsilon \times \left[\frac{2\epsilon}{q}\left(\frac{1}{N_A} + \frac{1}{N_D}\right)(V_{bi} - V_{app}\right.$$

$$\frac{1}{C^2} = \frac{2}{q\epsilon}\left(\frac{1}{N_A} + \frac{1}{N_D}\right)(V_{bI} - V_{app})$$



Only way to experimentally obtain built in voltages

Direct measure of the dopant density in P^+N / PN^+ diode case.

• AC Analysis (F.B)

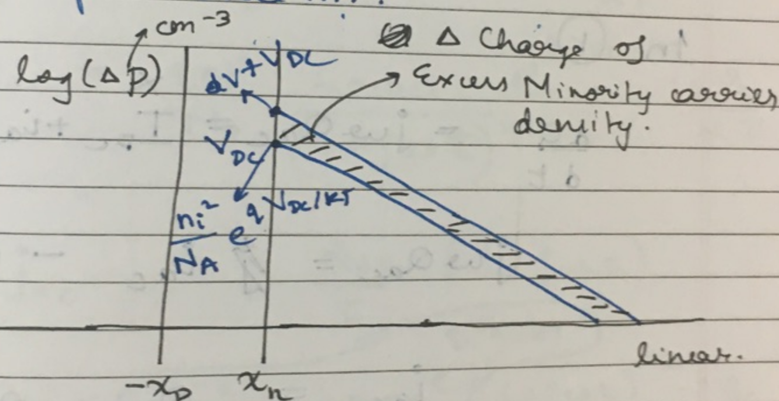
$$I = I_0\left(e^{qV/kT} - 1\right)$$

DC resistance: $\frac{V}{I}$

AC Resis. $= \left(\frac{dI}{dV}\right)^{-1}$

$$\frac{dI}{dV} = \frac{I_0 e^{qV/kT}}{\left(\frac{kT}{q}\right)} = \frac{I_{DC}}{\left(\frac{kT}{q}\right)}$$

- The previous case W modulation cap. will be there, in addition to that another capacitance .....



- Derivation

- Consider a p^+n junction

p^+	n

- Charge control Eqn.

$$\frac{dQ}{dt} = i_{diff} - \frac{Q}{\tau_p} \quad (1)$$

$$\boxed{Y = \frac{i_{ac}}{v_{ac}}} \rightarrow \text{our Goal!}$$

$$\cancel{j\omega Q_{ac} = I_{DC} + \ldots}$$

$$i = I_{DC} + i_{ac}$$ (Actually I values factor of e.s.A)

$$Q = Q_{DC} + Q_{ac}$$

$$\frac{dQ}{dt} = 0 + \frac{dQ_{ac}}{dt}$$

$$= j\omega Q_{ac}$$

In (1)

$$\frac{dQ}{dt} = j\omega Q_{ac} = \cancel{I_{DC}} + i_{ac} - \frac{\cancel{Q_{DC}} + Q_{ac}}{\tau_p}$$

$$j\omega Q_{ac} = i_{ac} - \frac{Q_{ac}}{\tau_p}$$

$$i_{ac} = \cancel{\frac{Q_{ac}}{\tau_p}} \quad Q_{ac}\left(\frac{1}{\tau_p} + j\omega\right)$$

$$= \frac{Q_{ac}}{\left(\frac{\tau_p}{1 + j\omega\tau_p}\right)}$$

$$I_{DC} = Q_{DC} / \tau_p$$

$$i_{ac} = Q_{ac} \Big/ \left(\frac{\tau_p}{1 + j\omega\tau_p}\right)$$ τ_{pac}

$$f_{ac} = \frac{q n_i^2}{N_A} e^{qV_{DC}/KT} \left(e^{qV_{ac}/KT} - 1\right) e^{-x/L_p}$$

$$Q_{ac} = \frac{q n_i^2}{N_A} e^{qV_{DC}/KT} \left(e^{qV_{ac}/KT} - 1\right) L_p$$

Area missing (~~Area~~ cm^{-2} (charge density) like σ)

$$Q_{ac} = \frac{q n_i^2}{N_D} L_p \, e^{qV_{DC}/KT} \cdot \frac{q v_{ac}}{KT}$$

σ_{ac}

$$Q_{ac} = \frac{q n_i^2}{N_D} \cdot \frac{L_{p(DC)}}{(1 + j\omega\tau)^{1/2}} e^{qV_{DC}/KT} \cdot \frac{q v_{ac}}{KT}$$

$$j_{ac} = \frac{Q_{ac}}{\tau} (1 + j\omega\tau)$$

$$= \frac{q n_i^2}{N_D} \times \frac{L_{p(DC)}}{\tau} e^{qV_{DC}/KT} (1 + j\omega\tau)^{1/2} \cdot \frac{q v_{ac}}{KT}$$

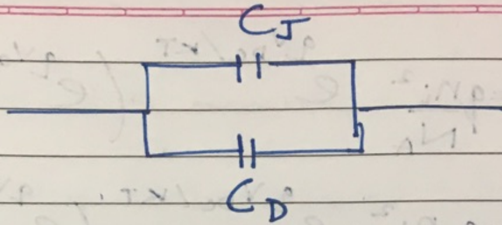
$\rightarrow J_{DC}$

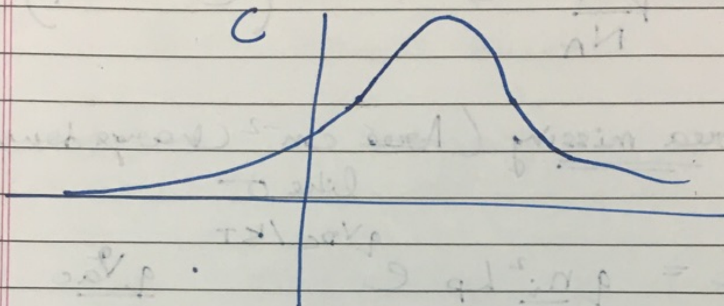
$$j_{ac} = J_{DC} (1 + j\omega\tau)^{1/2} \frac{q v_{ac}}{KT}$$

$$Y = \frac{j_{ac}}{v_{ac}} \Rightarrow \frac{j_{ac}}{v_{ac}} = \frac{J_{DC}}{\left(\frac{KT}{q}\right)} [1 + j\omega\tau]^{1/2}$$

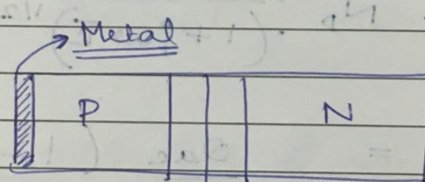
$$\boxed{Y = G_0 (1 + j\omega\tau)^{1/2}}$$

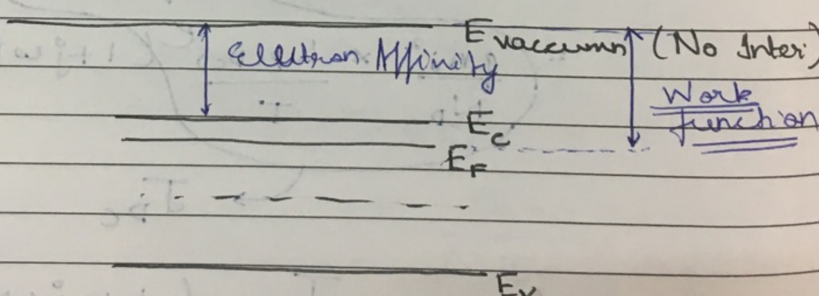
PAGE No. DATE / /



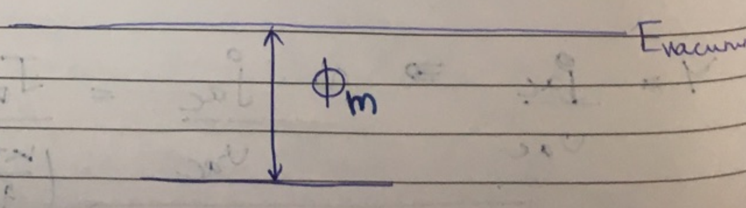


Metal - Semiconductor Contact

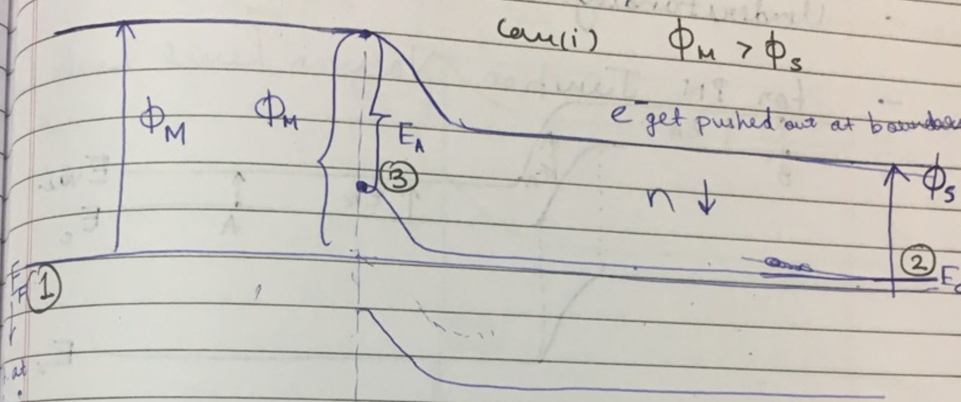


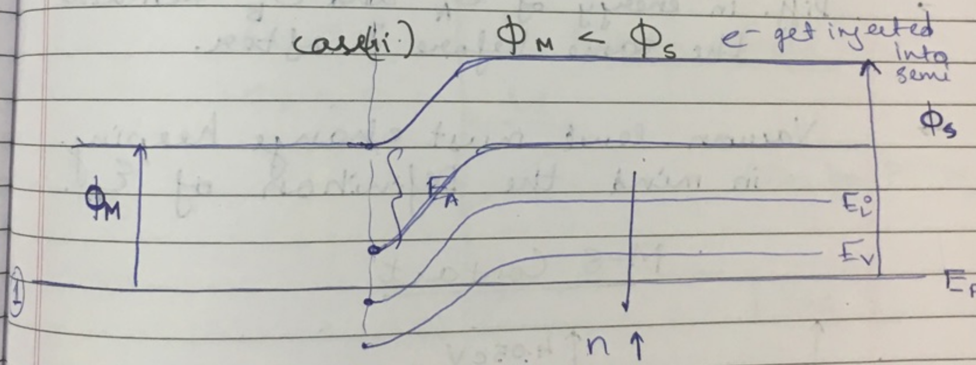


Metal



Combined band Diagram at Eq. of Metal - Semi. junction.





Lec - 34

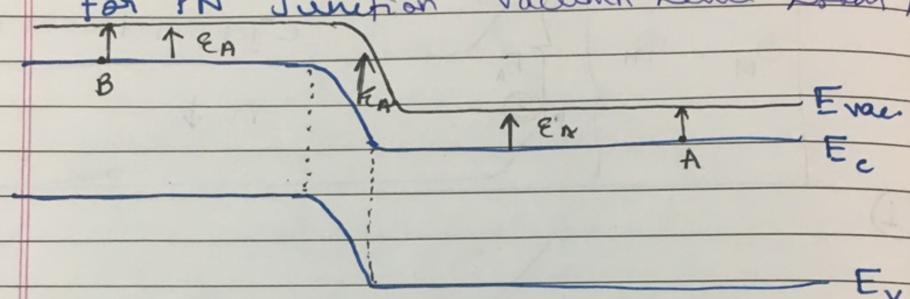
Plan, 2 extra lectures	Grading
SAT - 14/10/17	Quiz - 20%
SAT - 28/10/17	M.S - 25%
	Assign. - 5%
→ 2 extra quizzes 8/12	Endsem - 50%

PAGE No.
DATE / /

→ Metal - Semiconductor Contact

- Understanding Vacuum level.

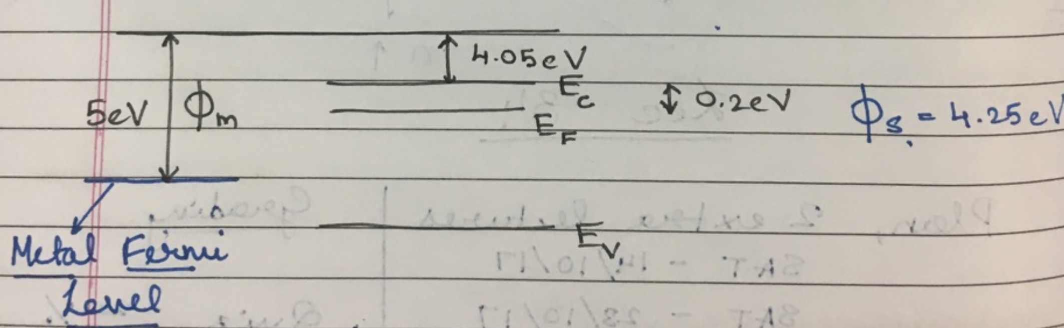
→ for PN Junction Vacuum Level Looks like.



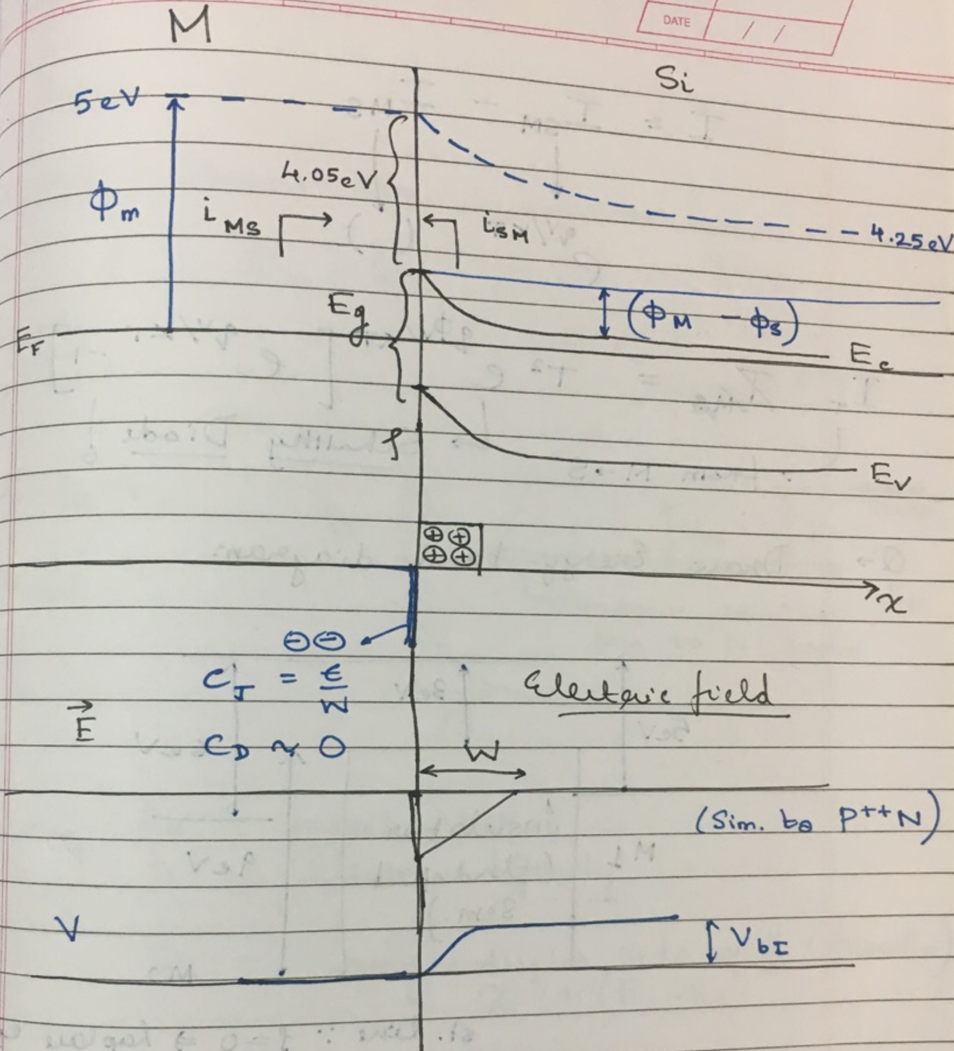
→ Diff. in energy of e^-_A and e^-_B remains the same before & after.

→ Vacuum level must change keeping in mind the Definition of ε_A.

M-S Contact



Dep. Approx.



→ Going from Metal to Sem. barrier is const.

→ Going from sem. to Metal

-ve bias → Barrier ↓ ⇒ current ↑
w.r.t metal

+ve bias → Barrier ↑ ⇒ current ↓
w.r.t metal.

PAGE No. DATE / /

$$I = I_{SM} - I_{MS}$$

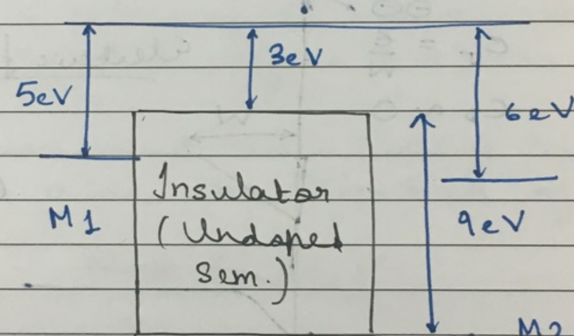
$I_{SM} \rightarrow e^{qV/KT}$, $I_{MS} \rightarrow (\ )$

$$I_T \quad \cancel{I_{MS}} = T^2 e^{q\phi_V/KT} \left[e^{qV/KT} - 1 \right]$$

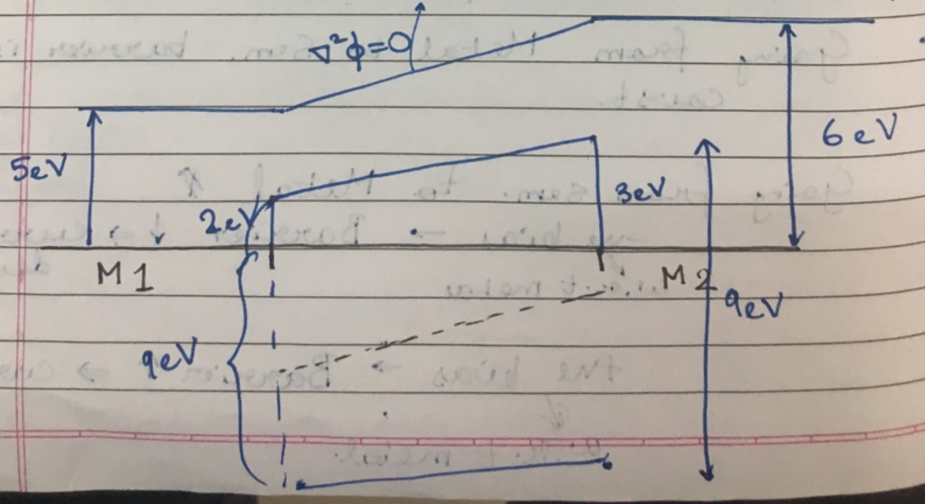
I_T → from M → S

↳ Schottky Diode !

Q → Draw Energy-band diagram



st. line ∵ $\rho = 0 \Rightarrow$ Laplace eqn.



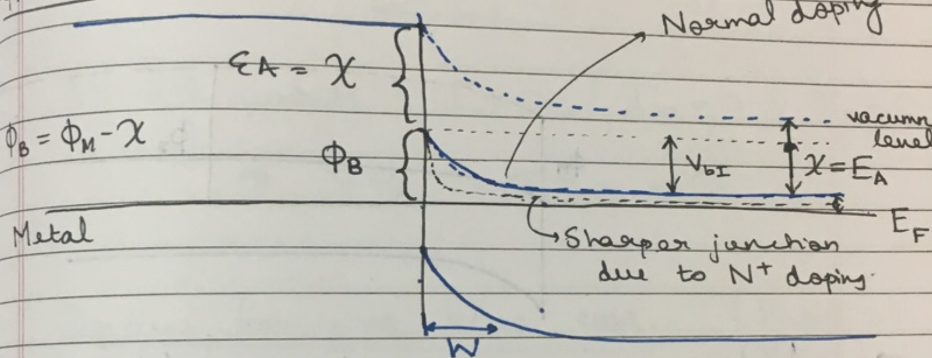
Lec - 35

Recap.

- MS - Metal - Semi. junction

$\phi_M > \phi_S$ → n-type semi.

$\phi_M > \phi_S$



ϕ_M - metal WF

χ - Electron Affinity

ϕ_s - Semiconductor side w.f (from E_F)

$= \chi + (E_c - E_F)$

$\phi_B = \phi_M - \chi$

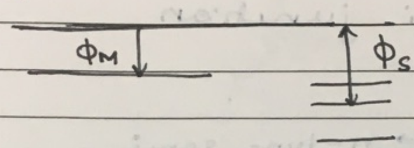
$V_{bI} = \phi_B - (E_c - E_F) = \phi_M - \phi_s$

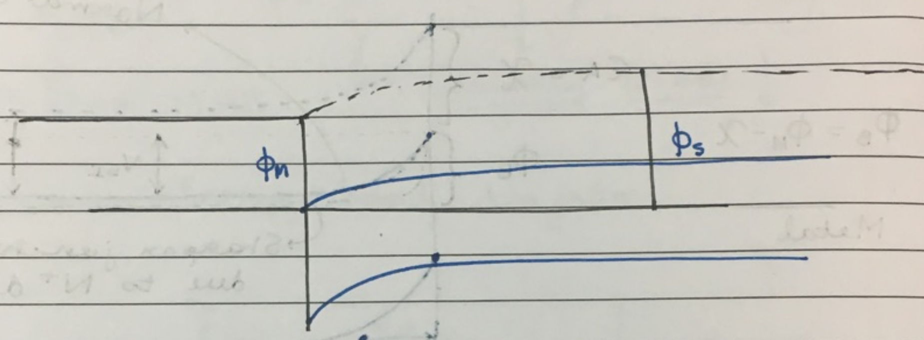
$I = (\ )\left[e^{qV/kT} - 1\right]$

Diff exp

- High Doping at junction, must start @ same pt. and go to a lower E_c $(E_c - E_F \downarrow)$

Case 2: $\phi_M < \phi_S$
↳ N-type.



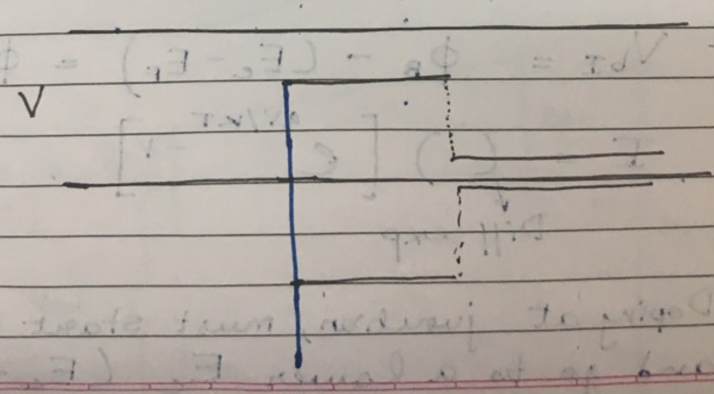


→ In this case no rectification/diode action
→ This is the desired behaviour but cannot be assured ⇒ high junction doping.

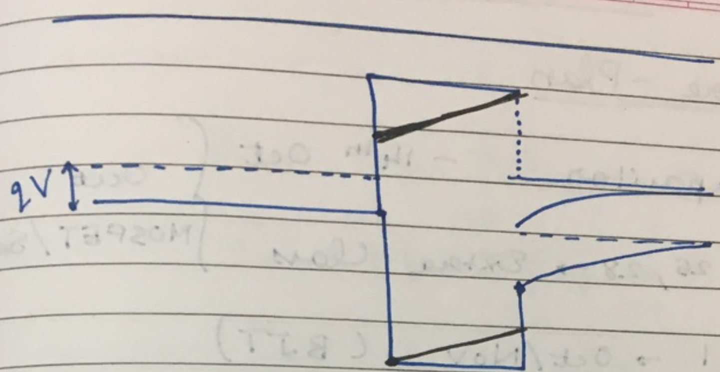
MOS Junction

(MOS → p-type)

→ $\phi_M = \phi_S$



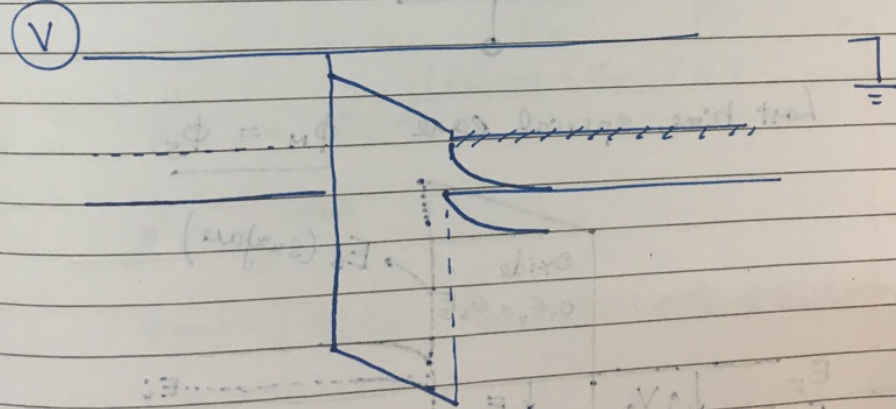
Part 1 : +ve Voltage



→ At all points $I = 0$, $I_n = 0$ & $I_p = 0$

$\Rightarrow \nabla E_{F_n} = \nabla E_{F_p} = 0$

→ Draw for -ve bias case. (Part 2) $(V < 0)$



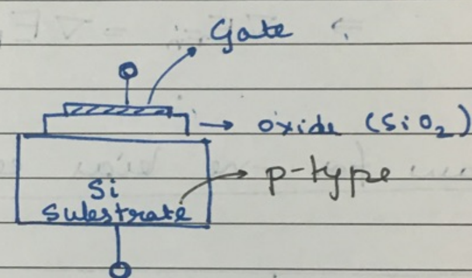
Lec - 36

Lecture - Plan

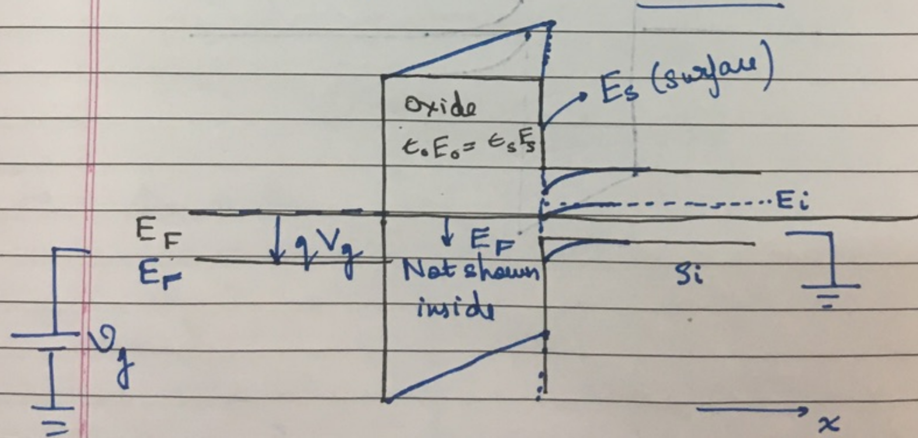
MOS Capacitor - 14th Oct
16, 17
22, 23, 25, 28 → Extra Class
29, 30, 1 → Oct/Nov (BJT)

Oct: MOSFET / Solar / LED

MOS Capacitor



→ Last time, special case $\phi_M = \phi_S$



$$\boxed{E_i(\infty) - E_i(x) = q\psi(x)}$$

PAGE No.
DATE / /

Current = 0

$$J_n = n\mu_n \nabla E_{Fn} = 0$$

$$J_p = p\mu_p \nabla E_{Fp} = 0$$

Analysis

$$\therefore E = -\nabla\psi$$

$$\nabla \cdot (\epsilon \nabla \psi) = -(p - n - N_A)$$

$$q\psi(x) = E_i(\infty) - E_i(x)$$

fine

$$p(\infty) = N_A \qquad n(x) = \frac{n_i^2}{N_A} e^{q\psi/KT}$$

$$n(\infty) = \frac{n_i^2}{N_A} \qquad p(x) = N_A e^{-q\psi/KT}$$

$$p(x) = n_i e^{(E_i(x) - E_F)/KT}$$

$$e^{(pow)}$$

$$pow = (E_i(x) - E_F - E_i(\infty) + E_i(\infty))/KT$$

$$\underbrace{n_i e^{(E_i(\infty) - E_F)}}_{N_A} e^{(E_i(x) - E_i(\infty))}$$

$$p(x) = N_A e^{-q\psi/KT}$$

$$n(x) = \frac{n_i^2}{N_A} e^{q\psi/KT}$$

$$\left\{ \begin{array}{l} \text{Constant } E_F \\ np = n_i^2 \end{array} \right.$$

PAGE No.
DATE / /

$$\epsilon \frac{d^2\psi}{dx^2} = -q\left(N_A e^{-q\psi/KT} - \frac{n_i^2}{N_A} e^{q\psi/KT} - N_A\right)$$

$$E = -\frac{d\psi}{dx}$$

$$\cancel{\frac{dE}{dx}} \quad \frac{dE}{d\psi} = \frac{dE}{dx} \times \frac{dx}{d\psi}$$

$$\Rightarrow \quad -E\frac{dE}{d\psi} = \frac{dE}{dx}$$

$$\cancel{\psi}\left(E\frac{dE}{\cancel{d\psi}}\right) = -\frac{q}{\epsilon}\left(N_A e^{-q\psi/KT} - \frac{n_i^2}{N_A} e^{q\psi/KT} - N_A\right)$$

$$\int_0^E E\,dE = -\frac{q}{\epsilon}\int_0^\psi \left(\quad \right) d\psi$$

$$\cancel{\frac{E^2}{2} = -\frac{q}{\epsilon}\left[\left(\frac{KT}{q}\right)e^{-q\psi/KT}\right.}$$

Cases on ψ

1) Accumulation phase :
Apply large negative bias.

$$\frac{E^2}{2} = N_A\left(\cancel{e^{-q\psi/KT}}^{\text{large}} \; \cancel{-\frac{n_i^2}{N_A} e^{q\psi/KT}}^{\sim 0} \; \cancel{-N_A}^{\sim 0 \text{ but consider}}\right)$$

$$\frac{E_s^2}{2} = \frac{\cancel{q}}{\epsilon}\left(\left(\frac{kT}{\cancel{q}}\right) N_A \, e^{-q\psi_s/kT}\right)$$

$$E_s = \sqrt{\frac{2N_A kT}{\epsilon}} \, e^{-q\psi_s/2kT}$$

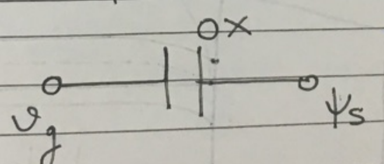
<u>Using Gauss Law</u>

$$E_s \cdot A = \cancel{A}\, \frac{q_{enclosed}}{\epsilon}$$

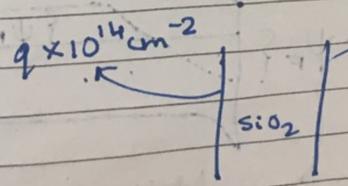
$$E_s = \frac{Q_s}{\epsilon} \quad cm^{-2} \text{ (per unit area)}$$

$$Q_s = \sqrt{2N_A \epsilon \left(\frac{kT}{q}\right) \times q} \; e^{-q\psi_s/2kT}$$

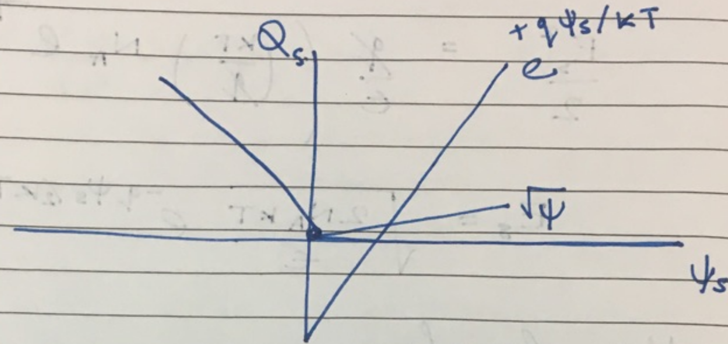
→ <u>Equivalent Capacitor</u>



→ Approx: No band bending



If we take entire drop across SiO_2 then ~ 10V at left.

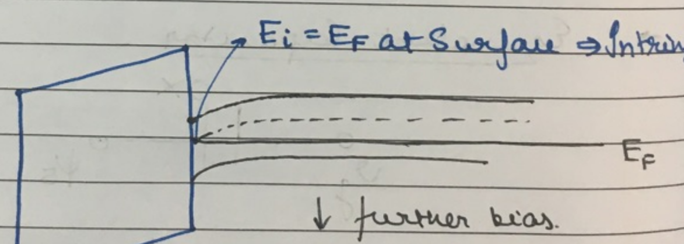


2) Depletion (Positive bias) (Low the bias)

$$\frac{E^2}{2} = \frac{-q}{\epsilon}\left(\frac{KT}{q}\frac{n_i^2}{N_A}e^{q\psi/KT} + N_A\psi\right)$$

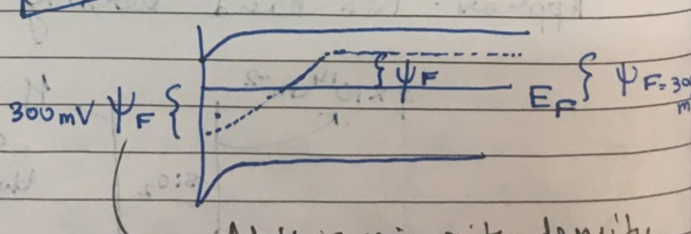
3) Inversion

Beyond a certain the voltage, band diagram becomes



↓ further bias.

→ Graph



At this minority density at Surface = Majority density in bulk.

PAGE No. DATE / /

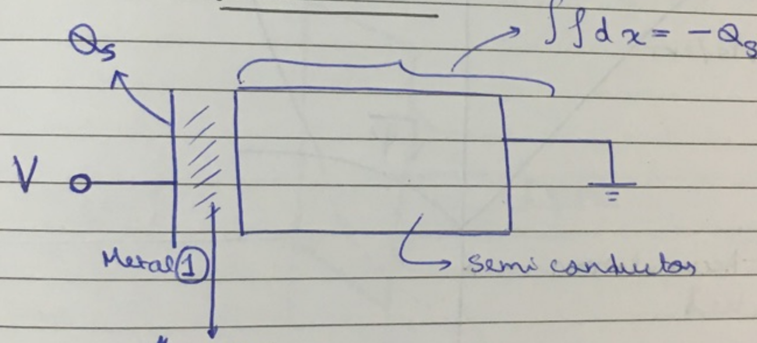
$$\frac{n_i^2}{N_A} e^{q\psi/kT} = N_A$$

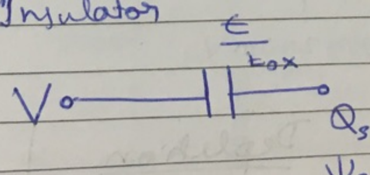
$$\frac{n_i^2}{N_A} e^{q(2\psi_F)/kT} = N_A$$

$$\ln\left(\frac{N_A^2}{n_i^2}\right) = \left(\frac{2q\psi_F}{kT}\right)$$

put $\psi_s = 2\psi_F + 8$ & check variation in R.H.S

Lec - 37





$$V = \psi_s + \frac{Q_s}{C_{ox}}$$

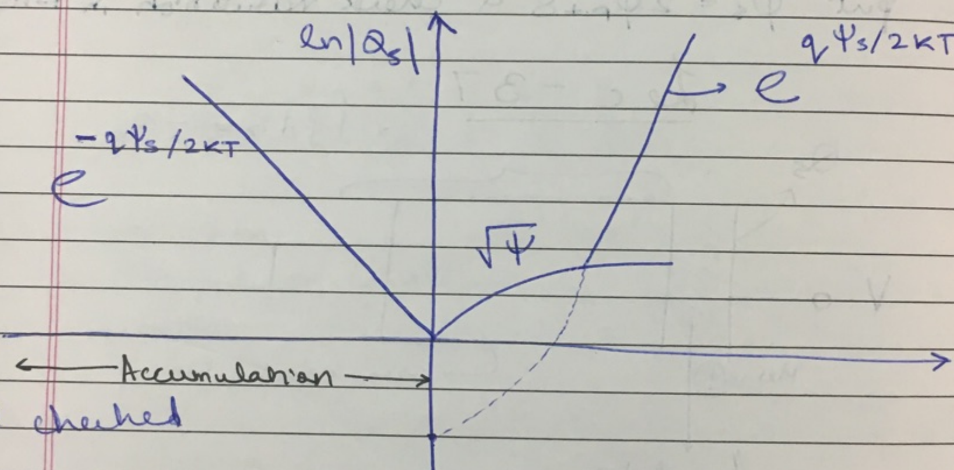
$$\epsilon \frac{d^2\psi}{dx^2} = -(p - n - N_A)$$

$$\frac{E^2}{2} = \frac{-q}{\epsilon}\int_0^{\psi_s} \left(\underbrace{N_A e^{-q\psi/kT}}_{\text{Majority}} \underbrace{- \frac{n_i^2}{N_A} e^{q\psi/kT}}_{\text{Minority}} - N_A \right) d\psi$$

$$E_s = \frac{Q_s}{\epsilon_s}$$

↓ Get the form

$$Q_s \sim \left[\frac{N_A e^{-q\psi_s/KT}}{\left(KT/q\right)} - \frac{\frac{n_i^2}{N_A} e^{q\psi_s/KT}}{\left(KT/q\right)} - N_A \psi_s \right]^{1/2}$$



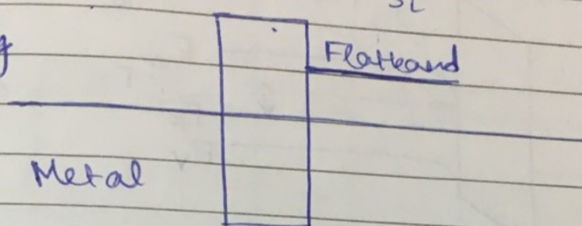
We checked

$10^{14} q\, cm^{-2} \Rightarrow 10V$ & $\psi \sim 250 mV$

Accumulation	Depletion	Inversion

→ When $\Phi_M = \Phi_S$ → Flatband condition ⇒ Equilibrium

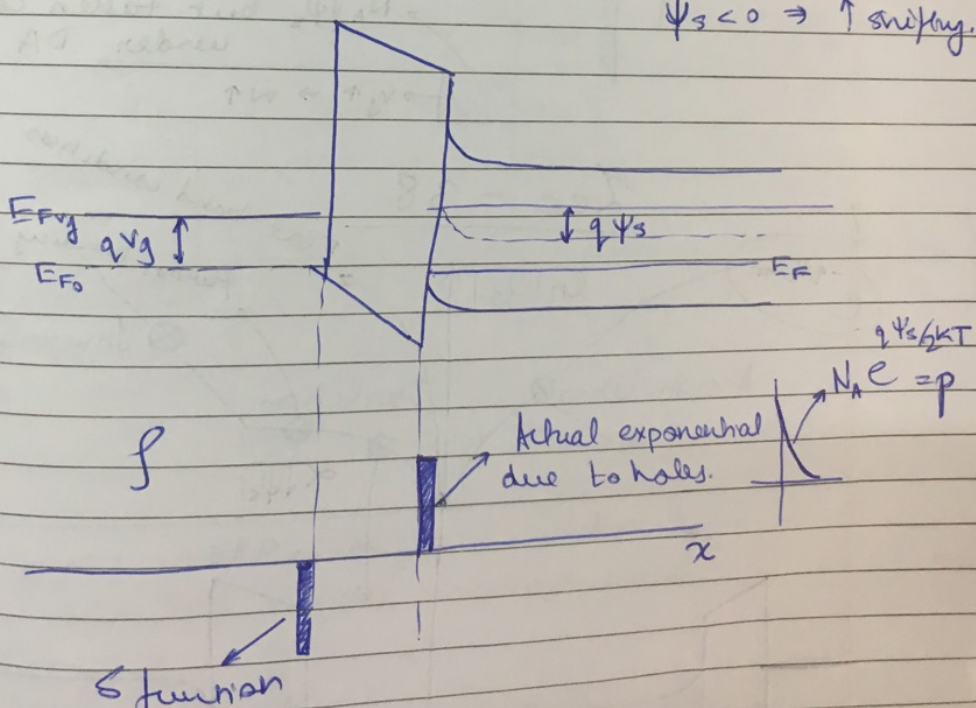
Apply $-V_g$



Accumulation

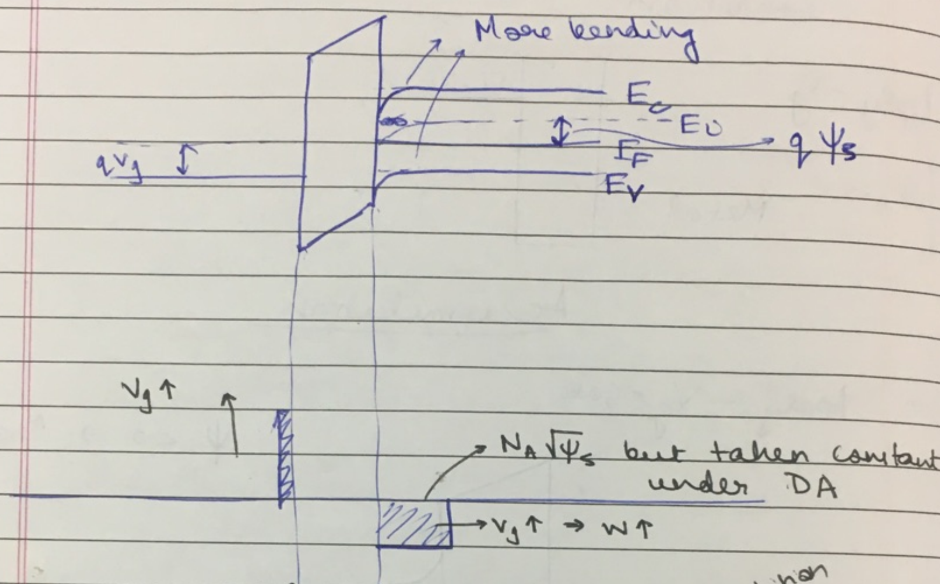
→ Apply $-V_g$ → gate.

$\psi_s < 0 \Rightarrow$ ↑ shifting.

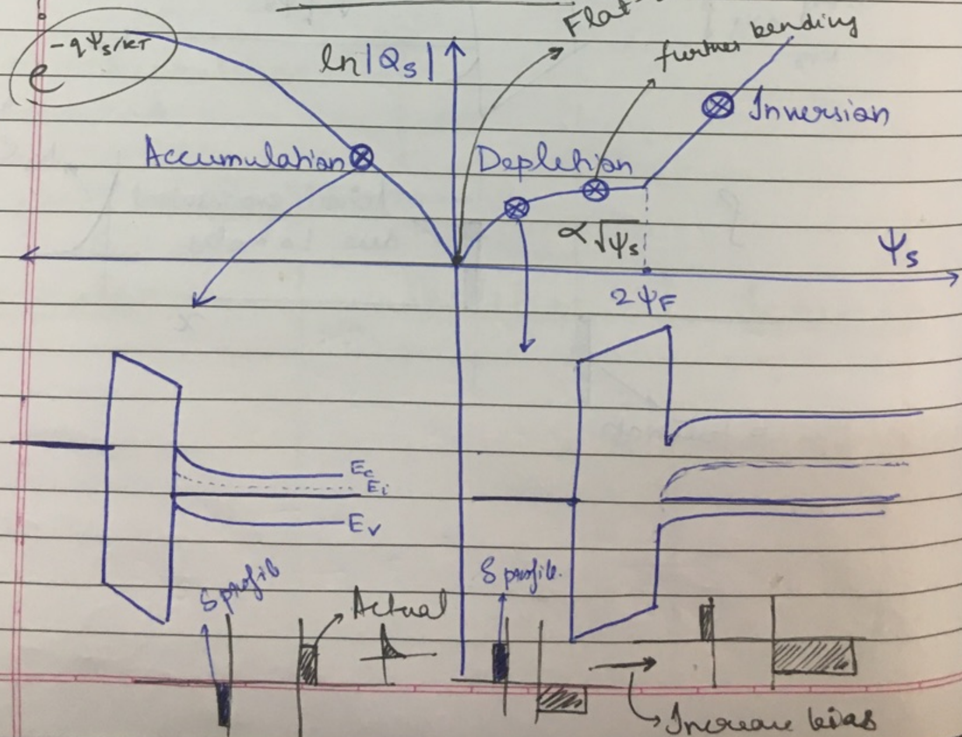


PAGE No.
DATE / /

Depletion $V_g > 0$, $\psi_s > 0$ but small

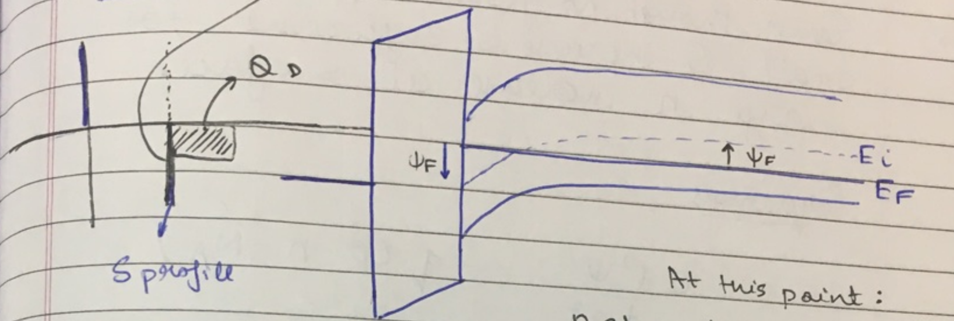


Lec - 38



$\rightarrow$ Appears After the onset of Inversion

Inversion



At this point:
n at surface = p in bulk

→ Condition of Strong Inversion

$$n_{surface} = P_{Bulk}, \quad n_s = P_b$$

$$\psi_F = \frac{kT}{q} \ln\left(\frac{N_A}{n_i}\right)$$

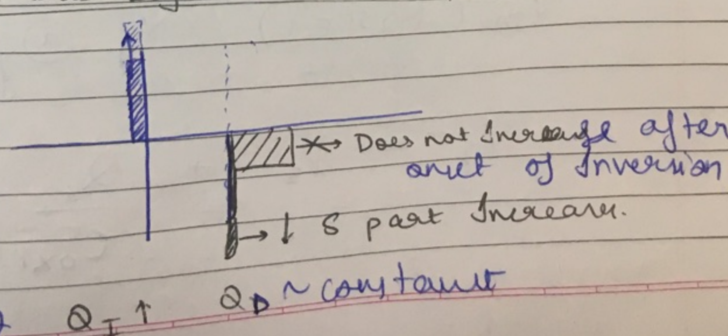
$\Rightarrow$ ψ_s at Strong inversion $= \dfrac{2kT}{q} \ln\left(\dfrac{N_A}{n_i}\right)$

- Alternatively:

$$e^{q\psi_s/kT} = \frac{N_A^2}{n_i^2}$$

$$\psi_s = \frac{2kT}{q} \ln\left(\frac{N_A}{n_i}\right)$$

Further bias beyond Inversion point



Beyond onset of Inversion $Q_I \uparrow$ $Q_D \sim$ constant

PAGE No.

DATE / /

→ Even though no further appreciable ↑ in ψ_s small δ increase is sufficient for large n increase at surface.

Equations

$$\epsilon \frac{d^2\psi}{dx^2} = -q(p - n - N_A)$$

$$\epsilon E \frac{dE}{d\psi} = -q(p - n - N_A)$$

$$Q_s^2 = (\epsilon E_s)^2 = 2\epsilon q \int_0^{\psi_s} (p - n - N_A)\, d\psi$$

$$p = N_A e^{-q\psi/kT} \qquad n = \frac{n_i^2}{N_A} e^{q\cancel{\psi}/kT}$$

$\psi + \delta\psi$

After onset of Inversion

Gate Voltage V_g

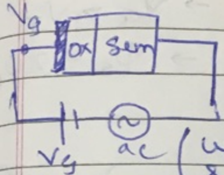
V_{TH} (MOSFET) $= V_g$ @ onset of Inversion

$$V_g = \psi_s + \frac{Q_s}{C_{ox}}$$

$$Q_s = (2 \epsilon q N_A \psi_s)^{1/2}$$

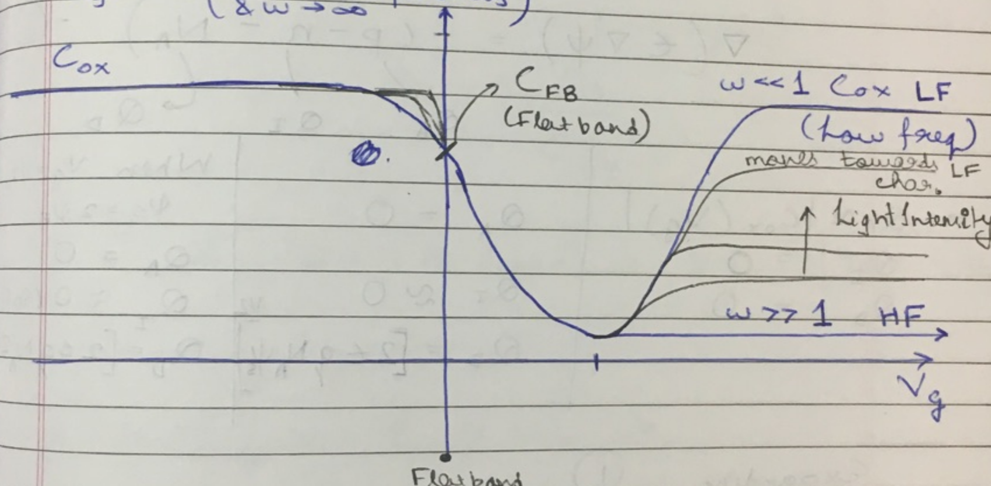
$$Q_s = q N_A W = (2 \epsilon q N_A \psi_s)^{1/2}$$

$$V_{TH} = 2\psi_F + \frac{Q_s}{C_{ox}}$$

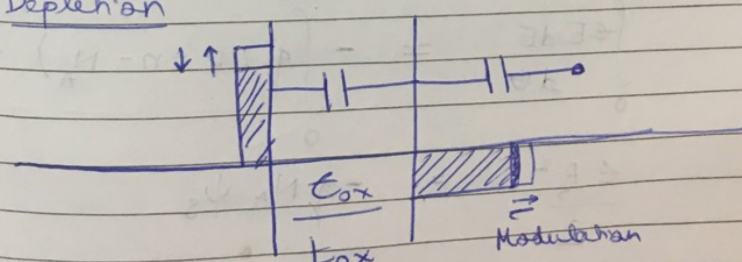


$C - V_{DC}$ Characteristics

($\omega \to 0$ & $\omega \to \infty$ separately)

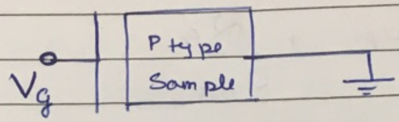


Depletion



Reference: Taur & Ning

MOS - CAP



Accumulation	Depletion	(Low) Inversion
→ $\psi < 0$, $\lvert\psi\rvert << 1$	→ $\psi << 1$	→ ~~$V_g > V_T$~~
→ Excess holes (Maj.) carrier at surface.	→ $\psi > 0$	→ $\psi_s = 2\psi_F$
	$\psi_s < 2\psi_F$	
	→ $V_g < V_T$	

$$\nabla(\epsilon \nabla \psi) = -(p - n - N_A) \quad -(1)$$

$p \to Q_A$, $n \to Q_I$, $N_A \to Q_D$

→ $Q_A \approx \lvert C_{ox}(V_g)\rvert$	$Q_A = 0$	When $V_g = V_T$, $\psi_s = 2\psi_F$
$Q_I = 0$	$Q_I \approx 0$	$Q_A = 0$
$Q_D = 0$	$Q_D = [2\epsilon q N_A \psi_s]^{1/2}$	$Q_I \approx 0$ (Still)
		$Q_D = [2\epsilon q N_A 2\psi_F]^{1/2}$

Expanding (1)

$$\int_0^E \epsilon E \frac{dE}{d\psi} = -\int_0^{\psi_s} q(p - n - N_A)\, d\psi$$

$$\frac{\epsilon E_s^2}{2} = -q N_A \psi_s$$

$$Q_s = \epsilon \lvert E_s \rvert = [2\epsilon q N_A \psi_s]^{1/2}$$

$V_T \approx V_t$

↳ threshhold voltage

→ Strong Inversion

→ $\psi_s \cong 2\psi_F + \delta \qquad (\delta << 1)$

$V_g > V_T$

Formulas

$$2\psi_F = (\psi_s)_I = \frac{2kT}{q} \ln\left(\frac{N_A}{n_i}\right)$$

$$V_g = \psi_s + \frac{Q_s}{C_{ox}}$$

$$V_T \text{ (At Gate)} = 2\psi_F + \frac{\boxed{4\epsilon q N_A \psi_F}^{1/2}}{C_{ox}}$$

$$V_{ox} = |\vec{E}_{ox}| \times t_{ox},$$

and $\epsilon_s|\vec{E}_s| = \epsilon_{ox}|\vec{E}_{ox}|$

$$V_{ox} = \frac{\epsilon_s |E_s|}{\epsilon_{ox}} t_{ox}$$

→ Strong Inversion

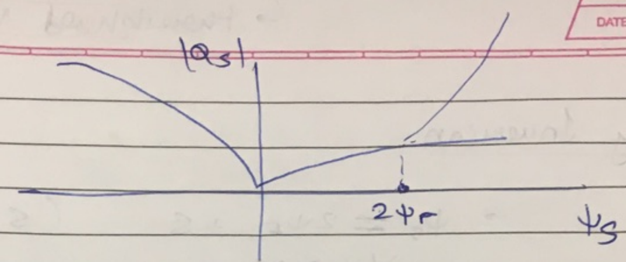
$Q_A = 0$

$\star\ Q_I = C_{ox}(V_g - V_t)\ \star$

$Q_D = [4\epsilon q N_A \psi_F]^{1/2}$

(Increases No further)

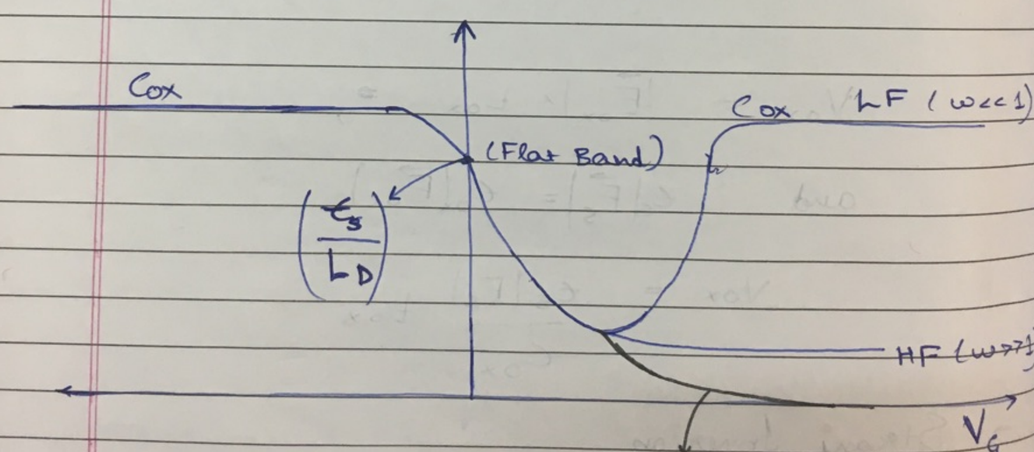
PAGE No. DATE / /



$$\epsilon E \frac{dE}{d\psi} = \frac{n_i^2}{N_A} e^{q\psi/KT}$$

$$\frac{\epsilon_s^2 E_s^2}{2} =$$

C-V Characteristics

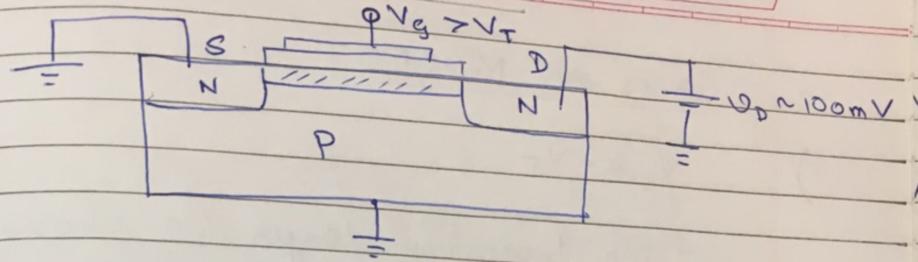


When $\frac{dV_g}{dt} >> 1$

- Increase in Inversion Layer can't keep up.

MOSFET

PAGE No. R(n)
DATE / /



$$Q_{IS} = C_{ox}(V_g - V_T)$$

$$Q_{ID} = C_{ox}(V_g - V_T - V_{DS})$$

$$I = \langle Q \rangle \langle v \rangle \qquad v = \mu \frac{V_{DS}}{L}$$

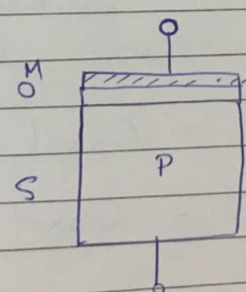
$$= \frac{(Q_{IS} + Q_{ID})}{2} \times \mu \frac{V_{DS}}{L}$$

24-10-17

Lec-39

office hours Wed 6-7pm
Sat/Sun → TBD

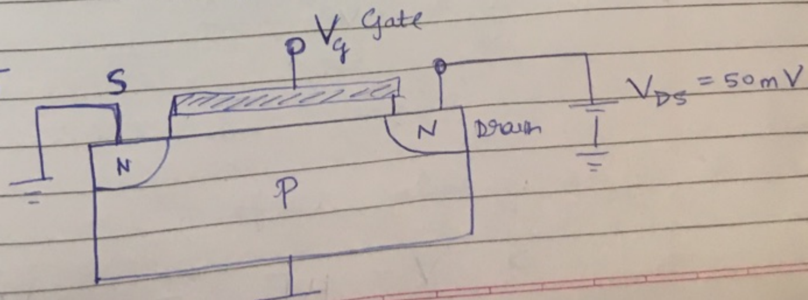
→ MOSCAP



$V_g > V_T$ (Inversion)

$$Q_I = C_{ox}(V_g - V_T)$$

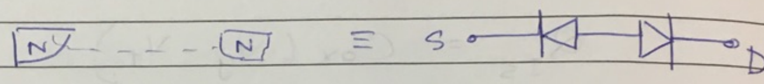
→ MOSFET



→ <u>Cases on</u> <u>MOSFET</u>

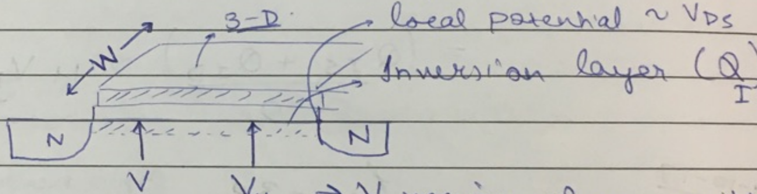
1) $V_g << V_T$

→ No Inversion layer (n-channel)



2) $V_g = V_T$ (or Greater)

→ Derive Current Expression



⇒ V varies along with position within Inversion layer

$$\Rightarrow \quad Q_I(S) = C_{ox}(V_{GS} - V_T)$$

$$\Rightarrow \quad Q_I(D) = C_{ox}(V_{GS} - V_T - V_{DS})$$

$$\frac{I}{W} = Qv \rightarrow \underline{\text{speed}}$$

↳ <u>3-D</u>

→ Effect is only drift.

$$\Rightarrow \quad v = \mu E = \mu \frac{V_{DS}}{L}$$

$$\frac{I}{W} = \mu \times C_{ox}\left(V_{gs} - V_T - \frac{V_{DS}}{2}\right)\frac{V_{DS}}{L}$$

spatial average

$$I = \frac{\mu W}{L} C_{ox} (V_{gs} - V_T) V_{DS}$$

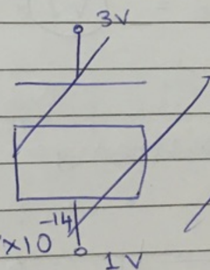
$C_{ox} \to \frac{\epsilon}{t}$

↳ Ignoring terms 2nd order in V_{DS}

$I \uparrow$ if $L \downarrow$ $t \downarrow$ $V_g \uparrow$

Q→ MOSCAP

Parameters



$V_T = 1V$

- $N_A = 10^{16}\ cm^{-3}$
- $t_{ox} = 3nm$
- $\epsilon_{ox} = 3.9 \times 8.8 \times 10^{-14}$

Find

→ V_T

→ $W_{depletion}$

→ CV

→ $\cancel{Q_s}$ $V_g = \psi_s + \frac{Q_s}{C_{ox}}$

$$\psi_F = \frac{kT}{q}\ln\left(\frac{N_A}{n_i}\right) \approx 360mV$$

$\psi_s = 2\psi_F \quad (\text{for } V_g = V_T)$

$Q_s(\psi_s = 2\psi_F)$

$= [4 \epsilon q N_A \psi_F]^{1/2}$

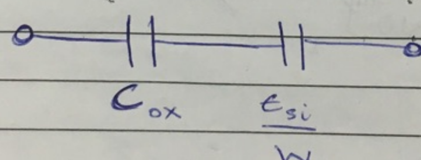
$= \ddot{q}$

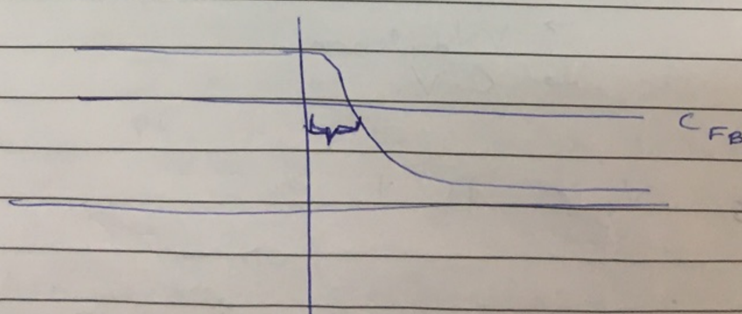
Get $V_T \approx 0.744$ V
$(720 + 24)$ mV

(*) Depletion width

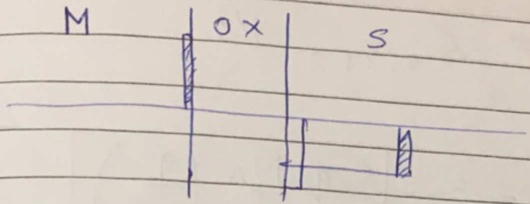
Use $Q_s = W \times (q N_A)$

(*) CV Characteristics





PAGE No. | DATE / /



Flat Band Condition ($V_g = 0$ Ideally)

$$Q_s^2 = \epsilon_s^2 E_s^2 = -2q\epsilon \int_0^{\psi_s} \left(N_A e^{-q\psi/KT} - N_A\right) d\psi$$

$$= -2q\epsilon \left[\frac{-N_A\left(e^{-q\psi_s/KT} - 1\right)}{q/KT} - N_A \psi_s \right]$$

$$= -2q\epsilon \left[\frac{-N_A}{q/KT} \left[\cancel{1} - \frac{q\psi_s}{KT} + \left(\frac{q\psi_s}{KT}\right)^2 \Big/ 2 - \cancel{1} \right] - N_A \psi_s \right]$$

$$\Rightarrow \frac{\cancel{2} q \epsilon N_A}{\cancel{2}} \left(\frac{q}{KT}\right) \psi_s^2$$

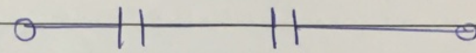
$$Q_s = \left[\epsilon q N_A \left(\frac{q}{KT}\right)\right]^{1/2} \psi_s$$

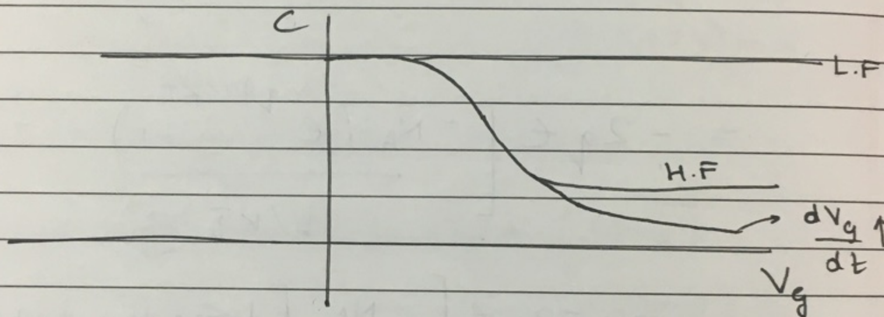
$$\cancel{Q} \quad \frac{dQ_s}{d\psi} = C$$

$$Q_s = C_{si(FB)} \psi_s$$

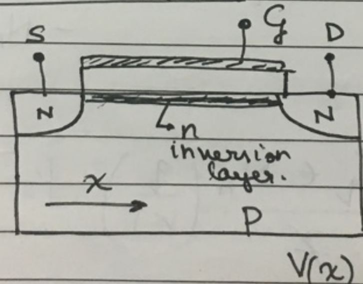
$$C_{FB} = \left[\epsilon q N_A \left(\frac{q}{kT} \right) \right]^{1/2}$$

C_{FB} =





→ MOSFETS Continued



$V_g >> V_T$
V_D is Small

$V_G >> V_T$, V_D is small

$$Q_I = C_{ox} (V_{gs} - V_T)$$

$$Q_I(x) = C_{ox} (V_{gs} - V(x) - V_T)$$

MOSFET

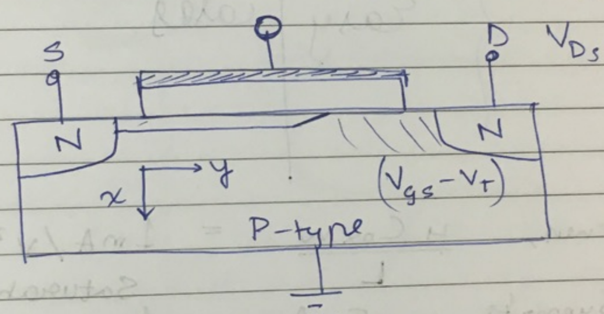
→ Sub-threshhold $V_g < V_T$

→ Linear $V_g > V_T$ $V_{DS} < V_g - V_T$

→ Saturation $V_g > V_T$, $V_{DS} > V_g - V_T$

$$I_{(Linear)} = \mu C_{ox} \frac{W}{L} \left((V_g - V_T) V_{DS} - \frac{V_{DS}^2}{2} \right)$$

$$I_{saturation} = \frac{\mu W C_{ox}}{2} \frac{(V_{gs} - V_T)^2}{L} (1 + \lambda V_{DS})$$



$$Q_I = C_{ox} (V_{gs} - V_T - V(y))$$

Alternate derivation

$$\frac{I}{W} = q \mu E \int_0^{\infty} n \, dx$$

E → Electric field

$$\frac{I}{W} = q \mu$$

$$I = \mu C_{ox} \left(\frac{W}{L}\right) \times \left[(V_{gs} - V_t) V_{DS} - \frac{V_{DS}^2}{2} \right]$$

Q→ Find the Regime of ~~operation~~

$V_T = 0.7V$

V_{DS} V	V_{gs} V
Easy	cases

Q→ Given, $\frac{\mu C_{ox} W}{L} = 1 mA/V^2$

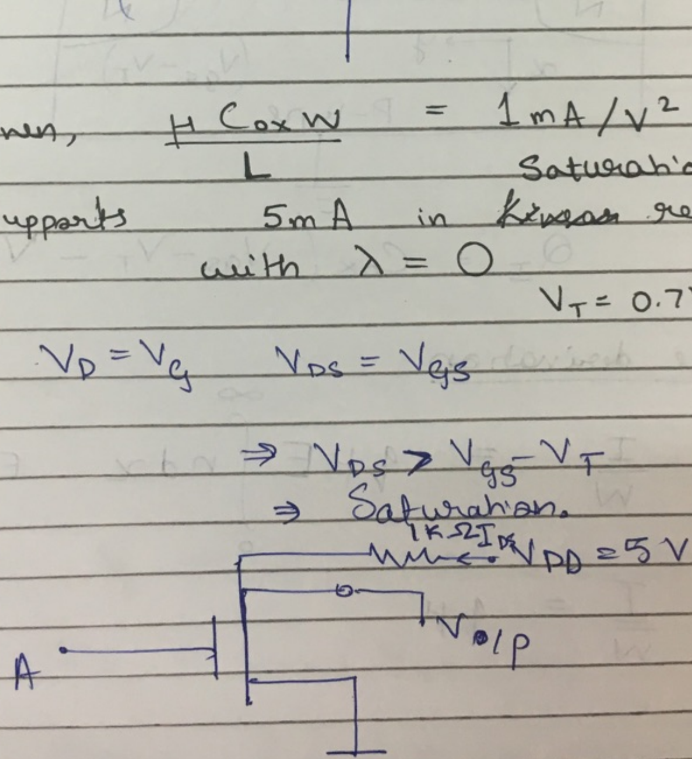
Supports 5mA in ~~Linear~~ Saturation region with $\lambda = 0$

$V_T = 0.7V$

(i) $V_D = V_g$ $V_{DS} = V_{gs}$

$\Rightarrow V_{DS} > V_{gs} - V_T$

$\Rightarrow$ Saturation.

(ii) 

$$5 - V_{DS} = 4.3V_{DS} - 0.5V_{DS}^2$$

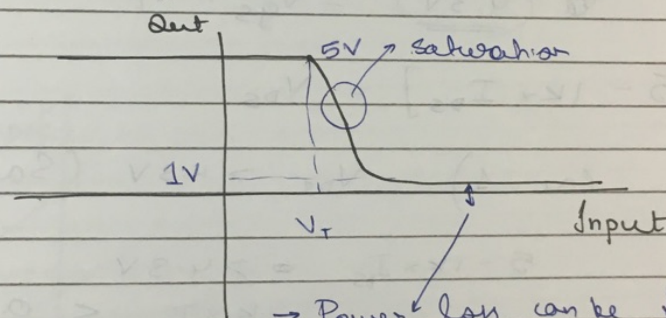
$$0.5V_{DS}^2 - 5.3V_{DS} + 5 = 0$$

$$V_{DS} = \frac{-0.5 + \sqrt{(5.3)^2 - 10}}{1}$$

$$V_{DS} = 1.04\,V$$

$\cancel{V_{DS} = 3.75}$ → Check again.

→ <u>Switching Char.</u>



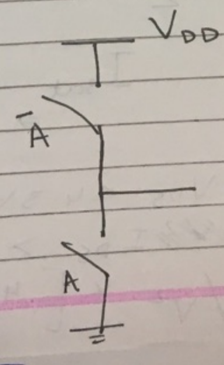
→ Power loss can be ↓

1K → 100K → V_{off} can be ↓ to 0

if we use high R

→ but $\tau = RC$ ↑ and switching time ↑

→ <u>Ideally</u>



Date: / /

$$\frac{\mu C_{ox} W}{L} = 1\,mA/V^2$$

A	O/P	(Capacitive load)
0V	5V	
5V	~~0.5V / 1V / 0.75V~~ 1.04V	(Linear region)

$V_A = 0V$

$V_A = 5V$

$4.3V = V_{gs} - V_T$

$[5 - 1K \times I_{DS}] = V_{DS}$

Case - 1) $V_{DS} > 4.3V$ (Saturation)

$5 - 1K \times I_{DS} > 4.3V$

$1K \times I_{DS} < 0.7K$

$I_{DS} < 0.7mA$

$$I_{sat} = \frac{1mA/V^2}{2} \times \cancel{} \times (4.3)^2 (1 + \cancel{\lambda V_{DS}})$$

$I_{sat} = 9.245\,mA$

$\Rightarrow$ Not Sat.

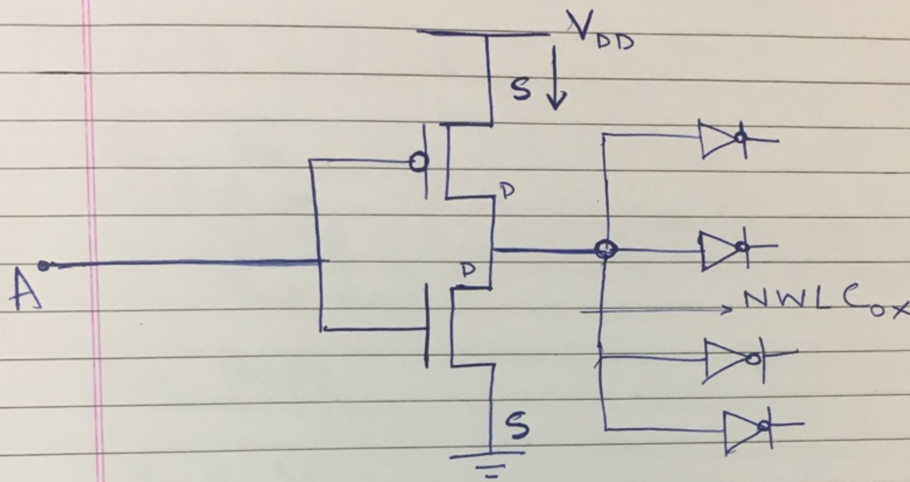
Linear

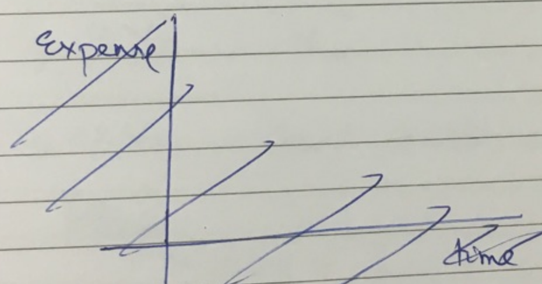
$V_{DS} < 4.3V$

$I_{DS} > 0.7mA$

$$1mA/\cancel{V^2} \times \left[4.3 \times V_{DS} - \frac{V_{DS}^2}{2}\right] = \frac{5 - V_{DS}}{\cancel{1K}}$$

→ Solution ⇒ Use CMOS





$\mu E = \mu \frac{V_{ds}}{2}$

$$Q_I(\,) = C_{ox}(V_{gs} - V_{DS} - V_T)$$

$$I = \mu C_{ox} \frac{W}{L}\left((V_{gs} - V_T)V_{DS} - \frac{V_{DS}^2}{2}\right)$$

Not bulk mobility (Much less)

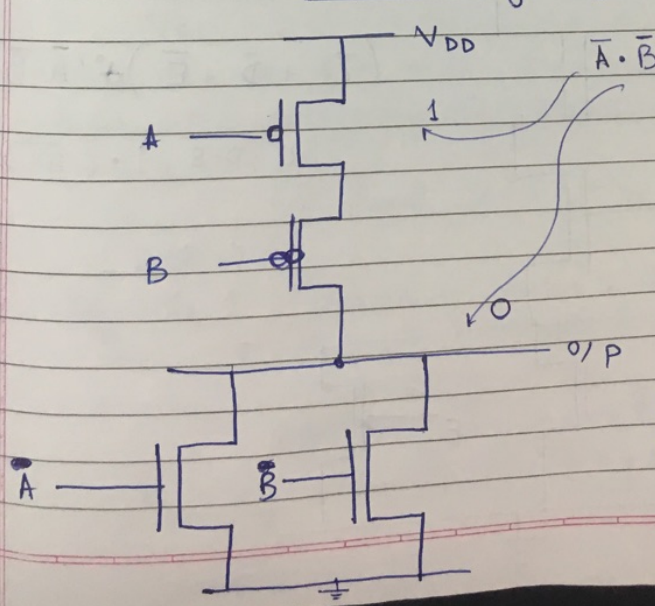
$\mu \to$ Mobility near surface, smaller due to roughness

For PMOS

1) $V_G < V_T$
2) $V_g > V_T$, $V_{DS} \sim$
3) $V_g >> V_T$ $\quad V_D$ is small

30-10-12 ~~Phase~~

MOSFET Logic Gates

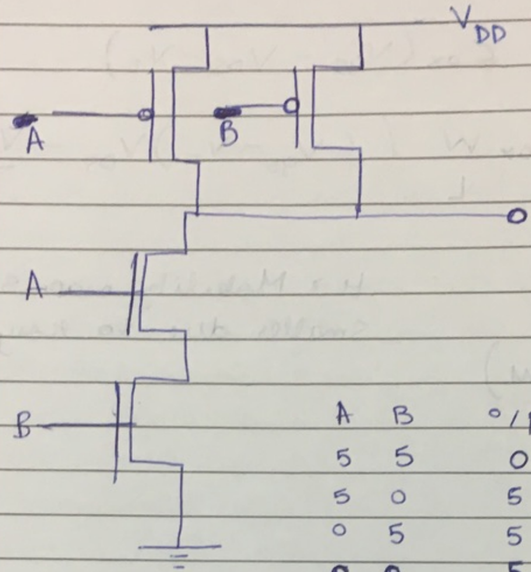


$\bar{A} \cdot \bar{B}$

$\overline{(A+B)}$

A	B	A+B	o/P
0	0	0	5
0	5	5	0
5	0	5	0
5	5	5	0

PAGE No. DATE / /



$\bar{A} + \bar{B}$

$\bar{A} \cdot \bar{B} + (\bar{A} + \bar{B})$

$= \bar{A} + \bar{B} = \overline{AB}$

$\overline{AB}$

A	B	o/p	AB
5	5	0	5
5	0	5	0
0	5	5	
0	0	5	

→ We want $\overline{AB(C+D+E)}$

$\overline{AB(C+D+E)}$

$(\bar{A}+\bar{B}) \cdot \bar{C} \cdot \bar{D} \cdot \bar{E}$

$= \cancel{(\overline{\bar{A}+\bar{B}}) + C + D + E}$

$\cancel{\overline{AB} + (C+D+E)}$

$= \cancel{\overline{AB} \cdot (C+D+E)}$

$\overline{AB} + (\bar{C} + \bar{D} + \bar{E})$

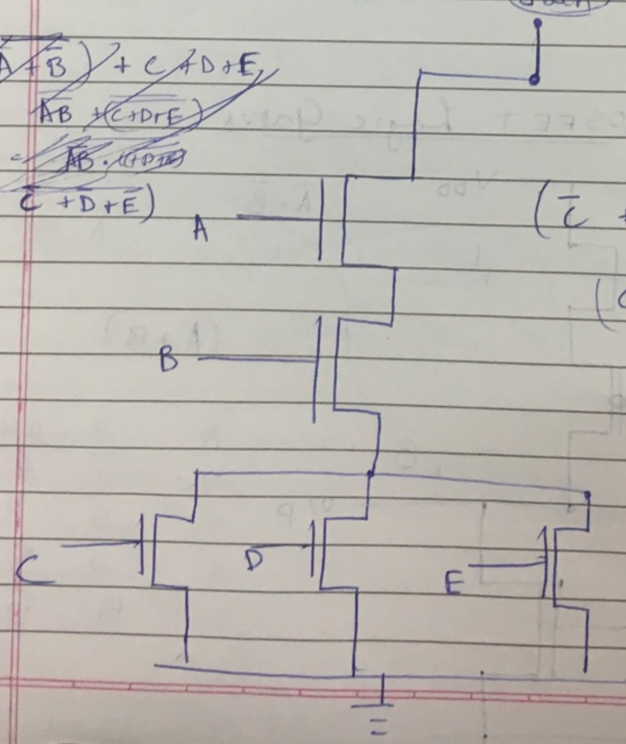
Join

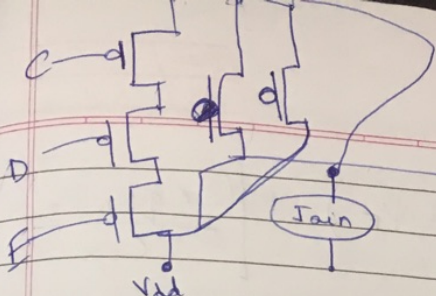
$\cancel{AB}B$

$(\bar{C} + \bar{D} + \bar{E}) \cdot (\bar{A} \cdot \bar{B})$

$(\overline{C \cdot D \cdot E}) \cdot (\overline{A+B})$

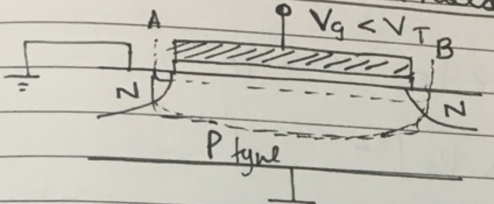
$C \cdot D \cdot E$



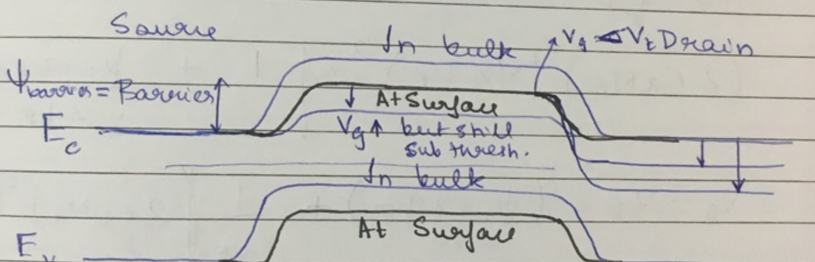


Corresponding PUN

Sub-Threshhold



(a) $V_D = 0V$ (b) $V_D = 0.3V$



→ At $V_{DS} = 0V$ → Complete symmetry ⇒ $I = 0$
→ At $V_{DS} > 0$ for sub threshhold, current is determined only by the barrier At left & hence,

for fixed V_g ($< V_t$) if $V_D\uparrow$, $I \sim k$

→ As $V_g\uparrow$, Barrier ↓ and $I\uparrow$ at sub threshhold
& $I \propto e^{-q\psi_{barrier}/KT}$

In this region

$$Q_s = (2\epsilon q N_A \psi_s)^{1/2}$$

$$V_g - V_F = \psi_s + \frac{(2\epsilon q N_A \psi_s)^{1/2}}{C_{ox}} - V_T$$

PAGE No.
DATE / /

$$V_g - V_T = (\psi_s - 2\psi_F) + \left[\frac{(2\epsilon q N_A \psi_s)^{1/2}}{C_{ox}}\right]$$

ψ_s just less than $2\psi_F$

$$\psi_s - 2\psi_F << 2\psi_F$$

$$[2\epsilon q N_A \psi_s]^{1/2}$$

$$= [2\epsilon q N_A (\psi_s - 2\psi_F + 2\psi_F)]^{1/2}$$

$$= \cancel{(2\epsilon q)^{1/2}}$$

$$(2\epsilon q N_A)^{1/2} \times (2\psi_F)^{1/2} \times \left[1 + \frac{\psi_s - 2\psi_F}{2\psi_F}\right]^{1/2}$$

$$V_g - V_T = (\psi_s - 2\psi_F) + \frac{1}{C_{ox}}\left[(2\epsilon q N_A)^{1/2} (2\psi_F)^{1/2}\right.$$

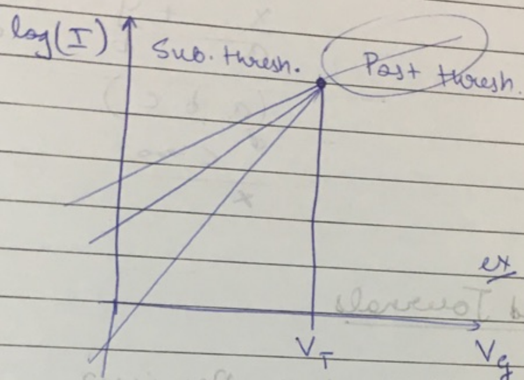
$$\cancel{(\psi_s - 2\psi_F) + \frac{1}{C_{ox}}}\Big[$$

$$V_g - V_T = (\psi_s - 2\psi_F) \times [1 + m]$$

Independant of ψ_s

$$m = 1 + \frac{(2\epsilon q N_A 2\psi_F)^{1/2}}{C_{ox}}$$

$$- \frac{(2\epsilon q N_A 2\psi_F)^{1/2}}{C_{ox}} \Big]$$



$$SS = \left(\frac{d(\log I)}{d V_g} \right)^{-1}$$

ex 60mV/dec

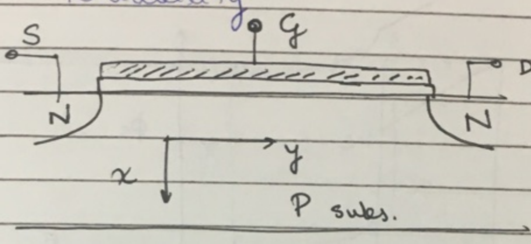
$$\Delta\psi_s = \frac{\Delta V_g}{m}$$

$$\left[\cancel{1/4} \; \frac{\psi_s - 2\psi_F}{4\psi_F} \right] \quad - \frac{(2\epsilon_q N_A 2\psi_F)^{1/2}}{\;} \Big]$$

Non-Ideal MOS

ϕ_{ms} $\quad Q_{ox}$ $\quad D_{it}$ $\quad V_T$ $\quad$ Short Channel Effects

Reliability



$E_{ox}(y) = \dfrac{\boxed{V_g - V(y)}}{t_{ox}} \times \epsilon_{ox}$

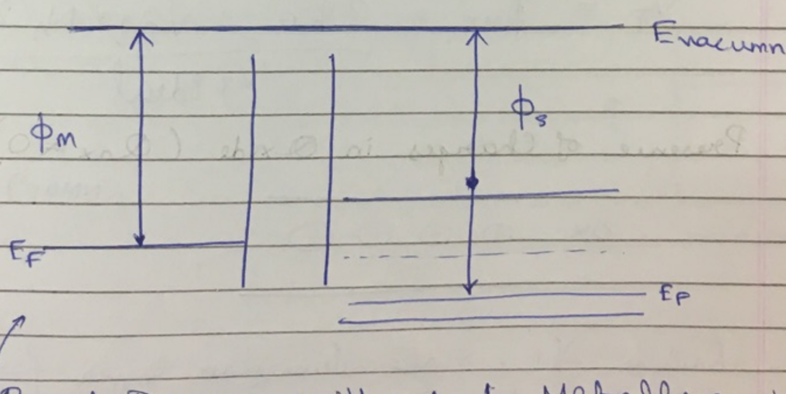
Q → ① I_D, NMOS, $V_T = 0.7V$, $V_{DS} = 0.5V$, $V_{gs} = 0.7V$

② $Q_I = C_{ox}(V_g - V_T - V(y))$

- For ① neither the Sub-threshhold I exp. nor the linear region exp. are valid

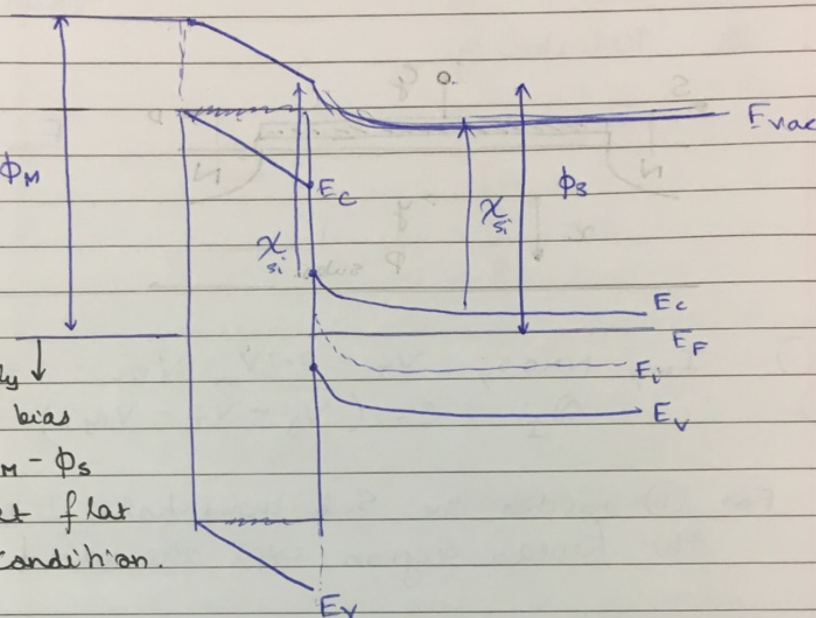
Band Diagram

$$\phi_{MS} = \phi_M - \phi_s \neq 0$$



→ Band Diagram without ! Metallurgical junction.

→ Equilibrium band Diagram



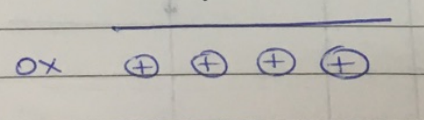
Apply ↓ the bias $= \phi_M - \phi_s$ and get flat band condition.

→ Hence all char. will shift by V_{fb}

$$\phi_{MS} = \phi_M - \phi_s \neq 0$$

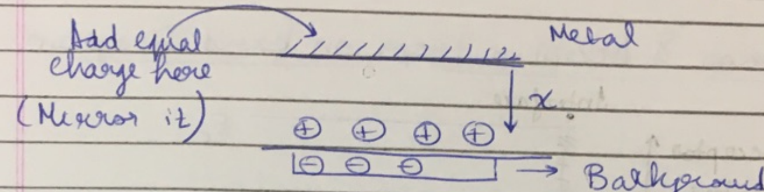
$$V_T = \phi_{MS} + \underbrace{2\psi_F + \sqrt{2q\epsilon N_A(2\psi_F)}}_{V_T \text{ ideal}}$$

→ Presence of Charges in Oxide ($Q_{ox} \neq 0$) (NMOS)



→ Lowers V_T, since Inversion layer forms earlier due to background deposition of charge.

→ Find Shift in V_T? What is V_{FB}



$$\Delta V_g = \frac{-\sigma}{\epsilon_{ox}} \times x$$

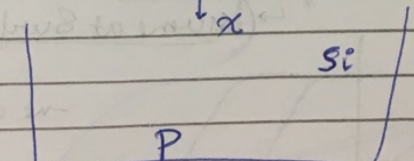
$\sigma \to \sigma(x)$

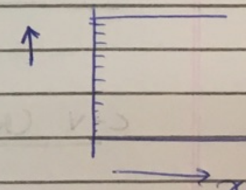
$$V_{FB} = -\int_0^{t_{ox}} \frac{\sigma x}{\epsilon_{ox}}\, dx$$

→ Immobile ions → C-V char. shifts by V_{FB}
→ Mobile ions → C-V char. further stretched out.

<u>Dit</u> : Interface state density

→ Dangling bonds/ traps/states @ surface



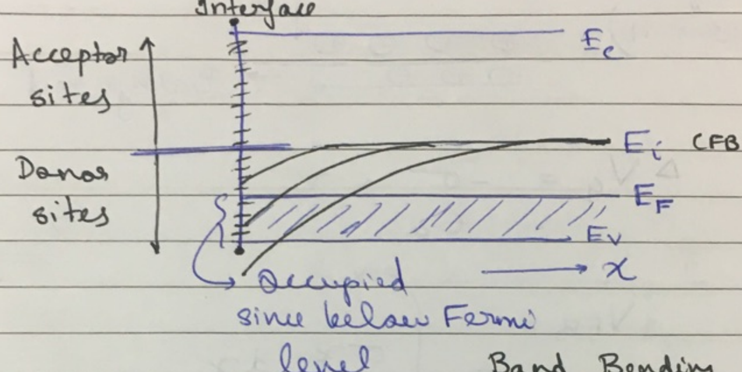


Empty states	Filled states (with e⁻!)	
+ve	0	Donor
0	-ve	Acceptor

Date: / /

→ Effect on Band Bending

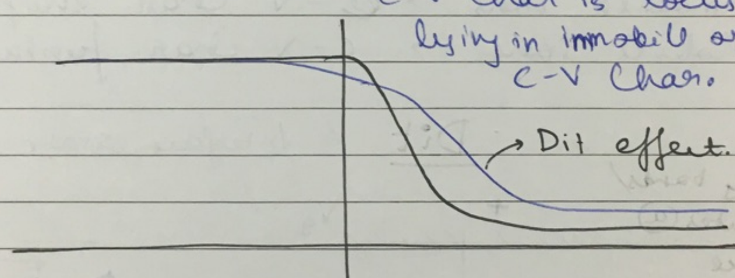
Donor & Acceptor traps on band Diagram



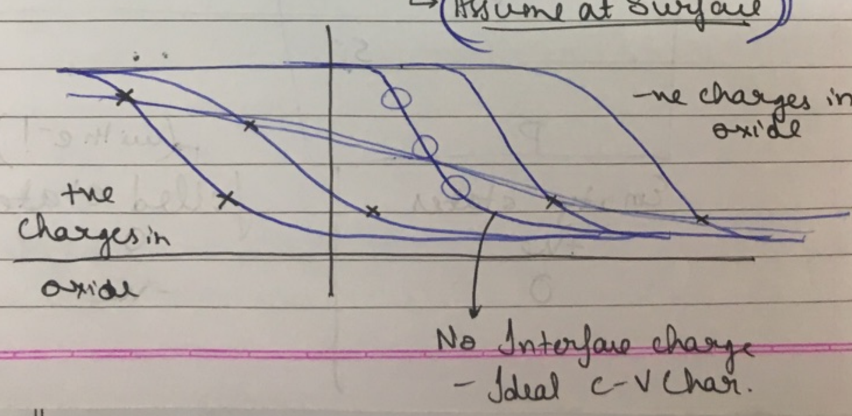
Band Bending

C-V Char.

- As E_i bends, nature of States changes hence final C-V Char is locus of points lying in immobile oxide charge C-V Char.



C-V Char. Charges in oxide & Dit effect relation
↳ (Assume at Surface)



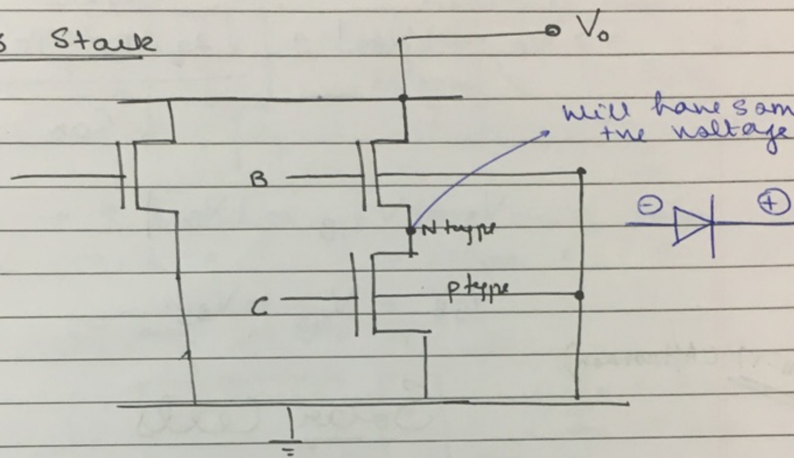
EE 207

2-11-17

→ Back Bias

- Plays Important Role in CMOS Stacks.

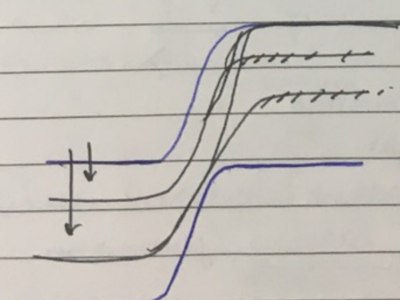
NMOS Stack



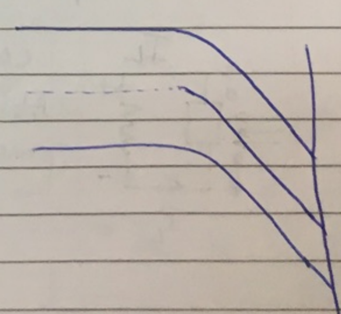
- Bodies Grounded Directly and source/drain will have some +ve potential.

→ This will change the threshhold point (Onset of Inversion)

S - B E - B Dia.



Vertical profile of Body



PAGE No.
DATE / /

$$\psi_S = 2\psi_F + |V_{BS}|$$

$$V_{Th} = 2\psi_F + |V_{BS}| + \frac{Q_0}{C_{ox}}$$

$$= 2\psi_F + |V_{BS}| + \frac{\sqrt{2q\epsilon N_A(2\psi_F + (V_{BS}))}}{C_{ox}}$$

$$V_T = V_{T,B} - |V_{BS}|$$

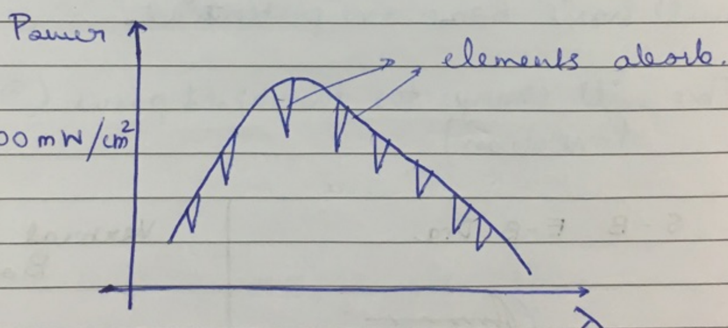
$$V_{GB} = V_{GS} - V_{BS}$$

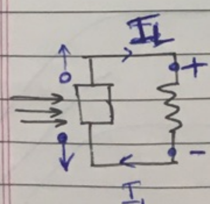
2-11-17 (Afternoon)

Solar Cells

Solar Energy

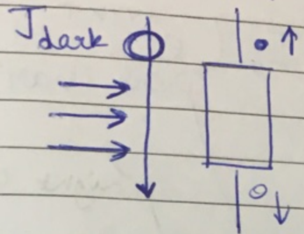
$P_{avg} = 100\ mW/cm^2$



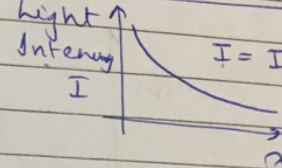


Characteristics
- Absorbs light
- We get current in external circuit
  ↳ through Carrier Generation
  ↳ free carriers not bound excitons
- Carriers should be collected at different terminals.

The voltage created by I_L by flowing through R, opposes the flow of I_L

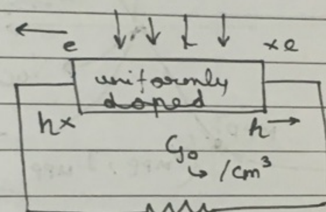


Absorption char.



$I = I_0 e^{-\alpha x}$ (x → depth)

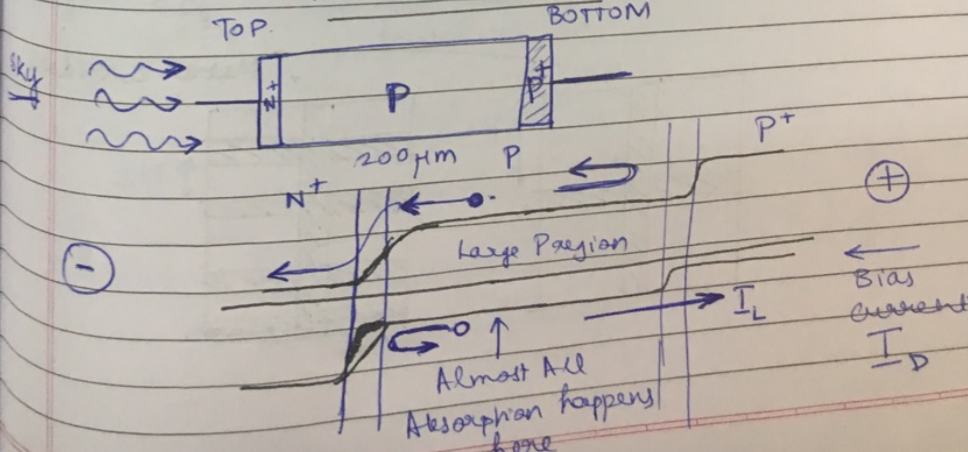
GaAs → ↑ Absorption ~ 1 μm thick Solar cells
Si → ↓ " ~ 200 μm " " "



$I_e = gL$
$I_n = gL$
$R = 0$

Note: If Electrodes were not special but Symmetric then No I due to
- Symmetry
- Recombination

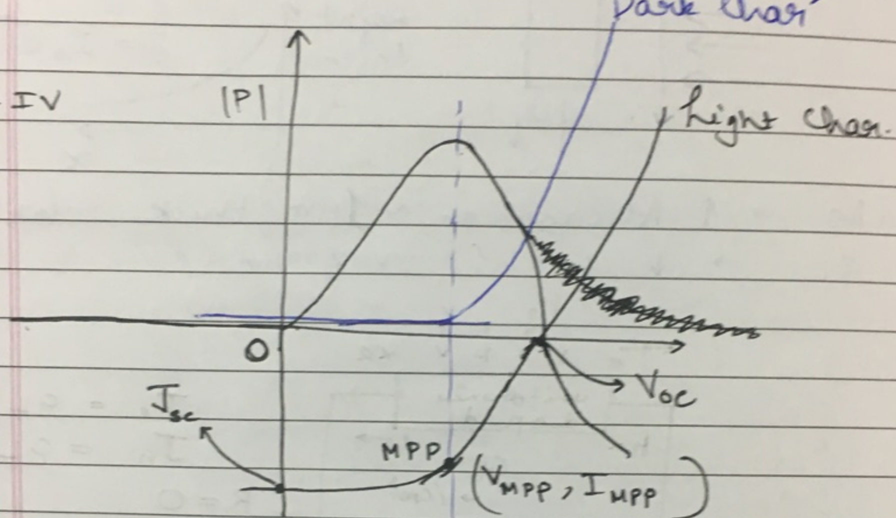
PN Junction



$$I_{Light} = -I_L + I_o\left(e^{qV/kT} - 1\right)$$

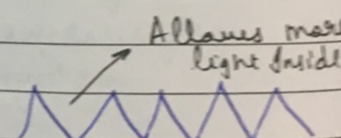
$$I_{dark} = I_o\left(e^{qV/kT} - 1\right)$$

P = IV

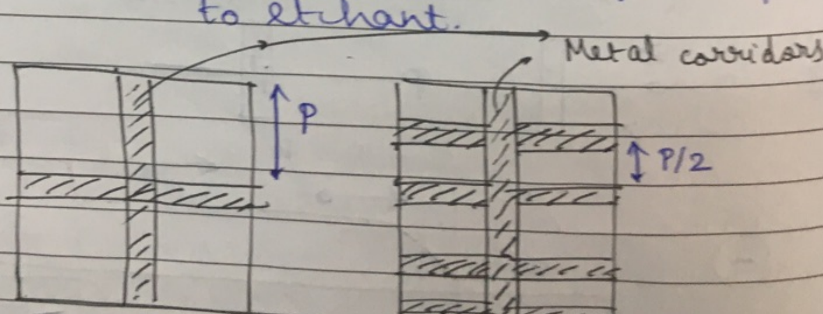


→ <u>Solar Cell Design</u>

- Eli Yablonovitch proposed Rough Surface →

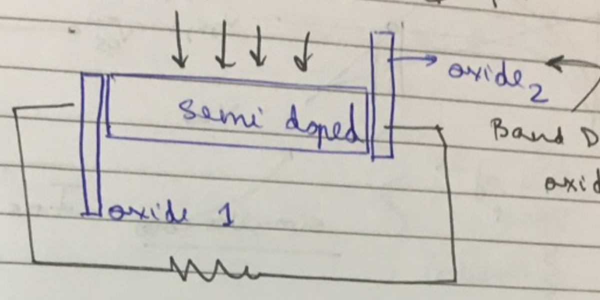


Expose Silicon ~~to~~ ~~Non~~ Non-Isotropically to etchant.



PAGE No. DATE / /

, Oxides with easy Metallurgy junction can be used to replace N^+ & P^+



Band Diagram with oxides

→ Relation with Band Gap E_g

$V_{oc} \downarrow \quad E_g \downarrow$

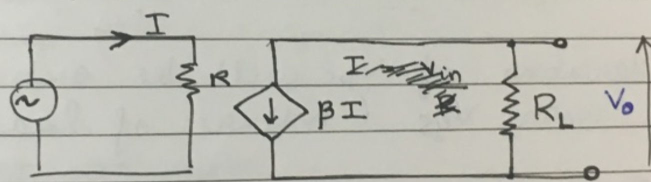
$I \uparrow \quad E_g \downarrow$

Hence trade-off

6.11.17

→ Amplification & Ammeter.

$A_V = \frac{V_o}{V_I} = \frac{\beta R_L}{R}$

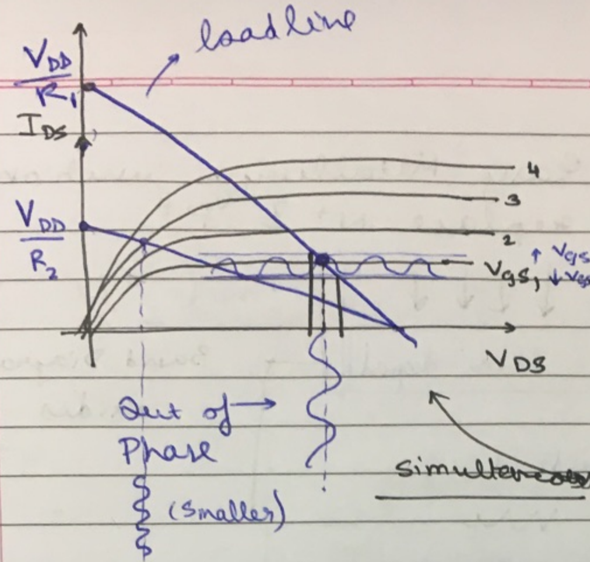


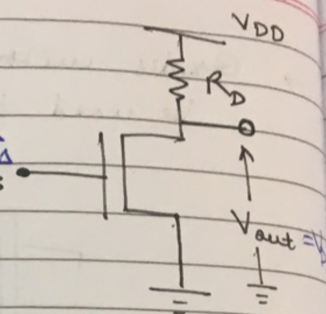
MOSFET as Amplifier

$$I_{DS} = \frac{\mu C_{ox} W}{L}\left[(V_{gs} - V_T)V_{DS} - \frac{V_{DS}^2}{2}\right]$$

(Sat.) $$I_{DS} = \frac{\mu C_{ox} W}{2L}\left[(V_{gs} - V_T)^2\right]$$

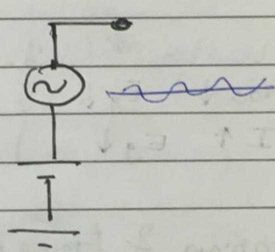
$R_2 > R_1$





$$I_{DS} = \frac{V_{DD} - V_{DS}}{R}$$

$V_{gs} \equiv$



→ Variation of V_{DS} will be out of phase with V_{gs} (Nature of load line)

→ Better to Bias in Saturation since we get more variation in V_{DS}
~~Mo~~ MOSFET Amps always biased in Sat.

→ Equivalent Ckt Model

$$I_{DS} + i_{DS} = I_{DS} + \frac{\delta()}{\delta}\Big|_{V_g}$$

$$I_{DS} = \frac{\mu C_{ox} W}{2L}\left[(V_{gs} - V_T)^2\right]$$

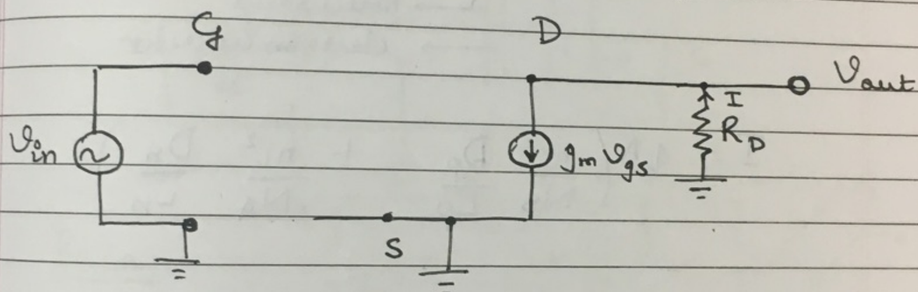
PAGE No.
DATE / /

$$i_{DS} = (\quad)^{??} v_{gs}$$

$$i_{DS} = \left(\frac{\delta I_{DS}}{\delta V_{gs}}\right)_{V_{ds}} = g_m v_{gs}$$

$$g_m = \frac{\mu C_{ox} W}{L}(V_{gs} - V_T)$$

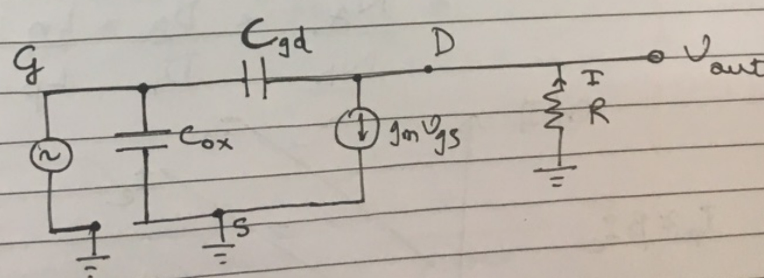
Model (AC. small Signal model)



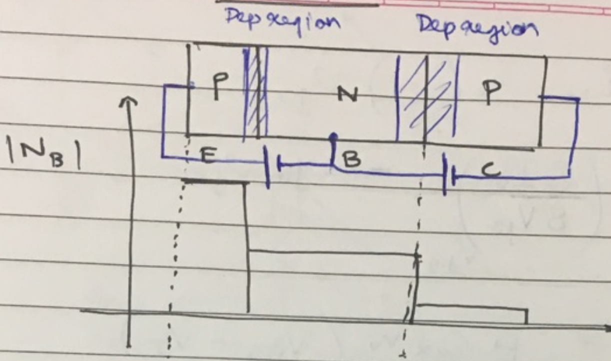
$$v_{out} = -g_m v_{gs} R_D$$

$$A_v = -g_m R_D$$

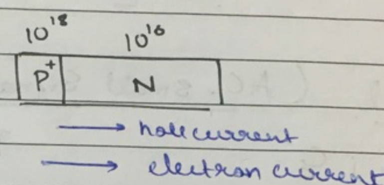
At hi-f



BJT



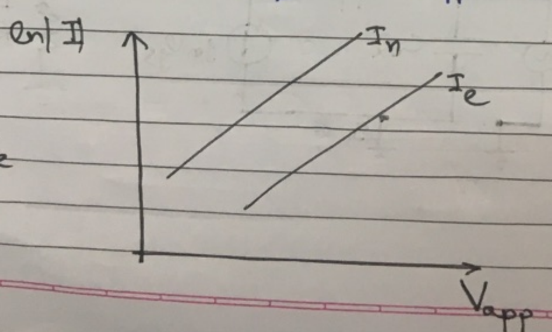
→ PN junction



$$I = qA\left(\frac{n_i^2}{N_D}\frac{D_p}{L_p} + \frac{n_i^2}{N_A}\frac{D_n}{L_n}\right)$$

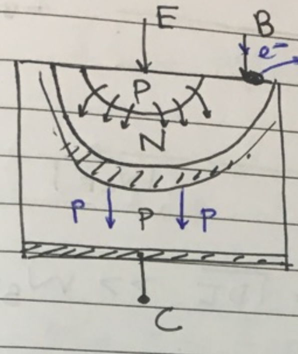
$$\beta = \left(\frac{I_h}{I_e}\right) = \frac{\frac{n_i^2}{N_D}\, D_p/L_p}{\frac{n_i^2}{N_A}\, D_n/L_n}$$

$$= \frac{N_A}{N_D} \times \frac{D_p}{D_n} \times \frac{L_n}{L_p}$$ → hidden dependent source.

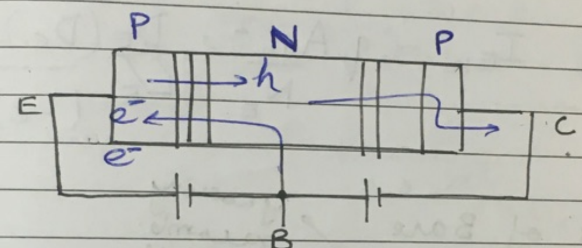


$I_p \approx \beta I_e$

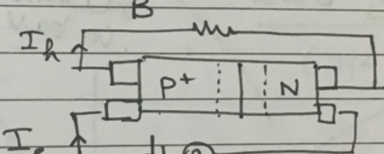
Split e & p currents to achieve goal.

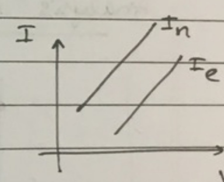


e^- located far away
all holes use other path

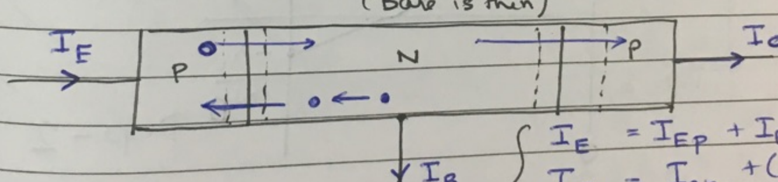


7.11.17 Recap



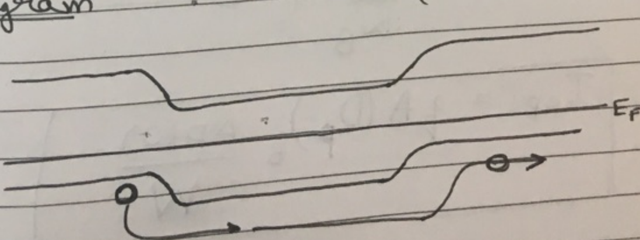


(Base is thin)

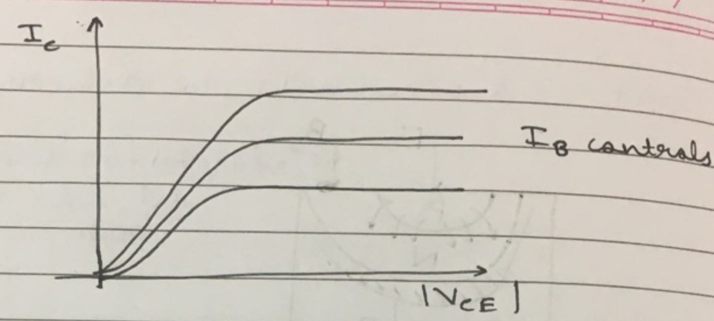


$$\begin{cases} I_E = I_{Ep} + I_{En} \\ I_B = I_{en} + (\text{Recomb.}) \\ I_{cp} = I_{ep} - (\text{Recomb.}) \end{cases}$$

E-B Diagram



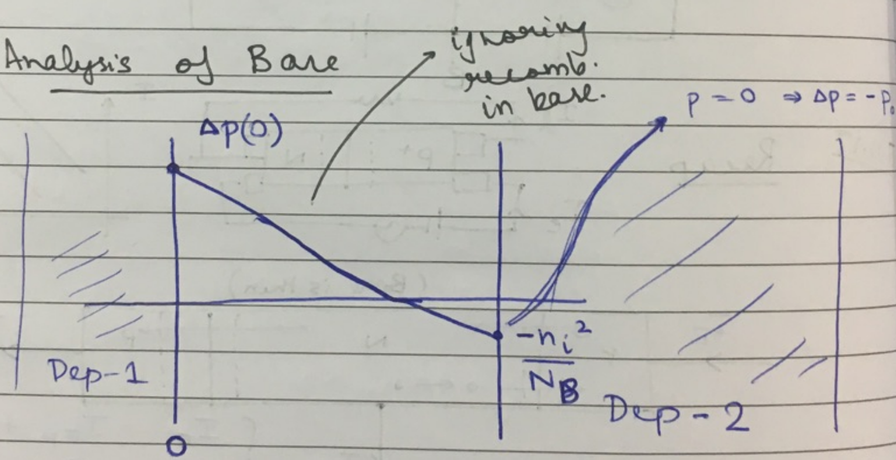
$\beta = \frac{I_c}{I_B}$



→ <u>Assumption</u> : $L = \sqrt{D\tau} >> W_B$

$I_{En} = qA\frac{n_i^2}{N_E} \cdot \frac{\cancel{D_E}}{\cancel{L_E}} \frac{(D_e)_E}{(L_e)_E} \left(e^{qV_{EB}/kT} - 1\right)$

<u>Analysis of Base</u>



$\Delta p(0) = \frac{n_i^2}{N_B}\left(e^{qV_{EB}/kT} - 1\right)$

$$\boxed{I_{cp} = qA(D_p)_B \frac{\Delta p(0)}{W}}$$

Now considering recombination

$$I(\text{recombination}) = \int_0^W \frac{\Delta n}{\tau}\, dx$$ Area under $\Delta p/p$ profile

$$I_{EP} = I_{CP} + \frac{qA\,\Delta p(0)\cdot W}{2\tau}$$

$$\alpha_T = \frac{I_{CP}}{I_{EP} + (\;)} = \frac{D_B/W}{D_B/W + W/2\tau_B}$$

$$= \frac{1}{1 + W^2/2D_B\tau_B}$$

$$\gamma = \frac{1}{1 + \frac{D_E}{D_B}\frac{W}{L_E}\frac{N_B}{N_E}}$$

$$\gamma = \frac{I_{EP}}{I_E}, \quad \gamma = \frac{qAD_B\,\Delta p(0)/W}{qAD_B\,\Delta p(0)/W + qA\frac{n_i^2}{N_E}\frac{D_E}{L_E}(\;)}$$

$$I_C = \frac{I_{CP}}{I_{EP}} \cdot \frac{I_{EP}}{I_E} \cdot I_E = (\gamma\alpha_T) I_E$$

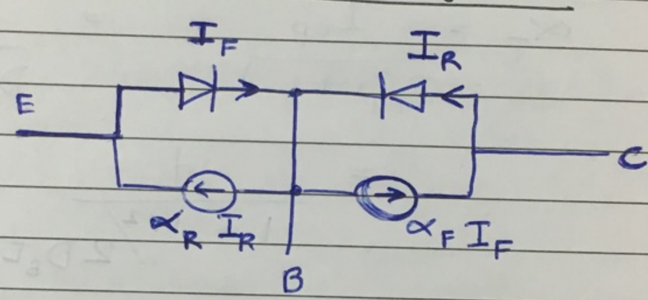
$$I_C = \alpha_{DC} I_E$$

PAGE No.
DATE / /

$$I_E = I_c + I_B$$
$$I_E = \alpha I_E + I_B$$
$$I_B = (1-\alpha) I_E$$

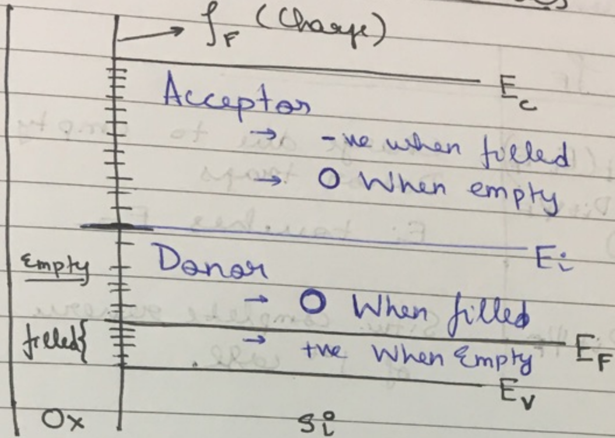
$$\beta = I_c / I_B = \left(\frac{\alpha}{1-\alpha}\right)$$

→ <u>Ebers - Bohl Model of BJT</u>

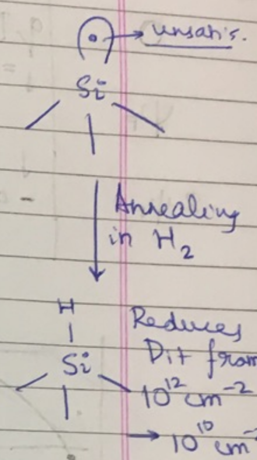


Interface States

· Nomen. based on N_A, N_D behaviour



D_{it} presence



→ Shift in Char.

$$V_g = \psi_s + E_{ox} t_{ox} \quad \text{— Always valid}$$

using $\epsilon_{ox} E_{ox} = \epsilon_{si} E_{si}$, we write

$$V_g = \psi_s + \frac{Q_{si}}{C_{ox}}$$

In absence of Interface Charges.

→ Electrostatics in presence of ρ_F

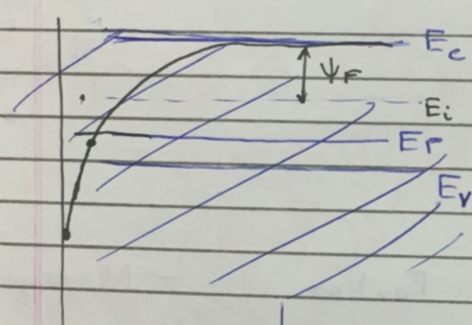
$$\epsilon_{ox} E_{ox} = \epsilon_{si} E_{si} + \rho_F$$
$$= Q_{si} + \rho_F$$

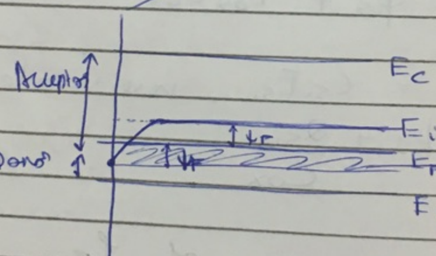
$$\Rightarrow V_g = \psi_s + \underbrace{\left[\frac{Q_{si}}{C_{ox}} + \frac{\rho_F}{C_{ox}}\right]}_{E_{ox} t_{ox}}$$

voltage modulated

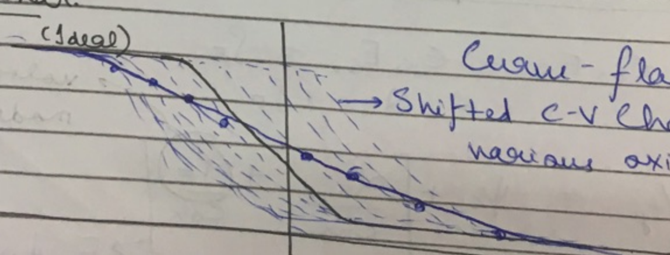
→ D_{it} : Taken as uniform (Approx.)
units : $cm^{-2} eV^{-1}$

ψ_s	ρ_F	
0	$q D_{it}(E_i - E_F)$ $= q D_{it} \psi_F$	Charge due to empty Donor traps
ψ_F	0	E_i touches E_F
$2\psi_F$	$-q D_{it} \psi_F$	Situ. complete reverse of 1st case.





C-V Char.



Curve - flattens out.
→ Shifted C-V Char. for various oxide charges

$$\psi \to \psi + \Delta\psi$$

$$I \to I + \Delta I$$

$$\Delta V_g \quad + \frac{q D_{it} \Delta\psi}{C_{ox}}$$